

ETSI EN 301 489-1 V1.8.1 (2008-04)  
ETSI EN 301 489-6 V1.3.1 (2008-08)

## TEST REPORT

For

**Xingtel Xiamen Group Co., Ltd.**

Xingtel Building, Chuangxin Road, Torch Hi-Tech Industrial District,  
Xiamen 361006, PR China

**Model: i-700**

<b>Report Type:</b> Original Report	<b>Product Type:</b> iPhone Complimate
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<b>Report Number:</b> RSZ111017004-02a	
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\* This report contains data that are not covered by the NVLAP accreditation and are marked with an asterisk "★" (Rev.2)

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DRAFT

## GENERAL INFORMATION

### Product Description for Equipment under Test (EUT)

The Xingtel Xiamen Group Co., Ltd.'s product, model number: i-700 or the "EUT" in this report was a *iPhone Complimate*, which was measured approximately: 17.89cm (L) x 10.6cm (W) x 4.3 cm (H) for base, and 16.2 cm (L) x 5.0 cm (W) x 2.4 cm (H) for handset, rated input voltage: DC 6V from adapter for base and DC 1.2V × 2 AAA battery for handset.

Adapter information: AC power adapter  
Model: MN-A006-E130;  
Input: 100-240V~50/60Hz, 0.3A Max;  
Output: DC 6V, 700mA / DC 6V, 300mA

*\* All measurement and test data in this report was gathered from production sample serial number: 1110045 (Assigned by BACL, Shenzhen). The EUT was received on 2011-10-17.*

### Criterion A

#### Performance criterion for Continuous Phenomena applied to DECT Phone Transceivers part

The BER of the signal as measured shall not exceed  $1 \times 10^{-3}$  during the test sequence.

Additionally for equipment containing analogue speech circuits the speech output signal level shall be at least 35dB less than the previously recorded reference level. At the conclusion of the test, the EUT shall operate as intended with no loss of user control functions or stored data and the communications link shall have been maintained during and after tests. Where the EUT is capable of transmission, tests shall be performed to ensure that unintentional transmission does not occur. The apparatus shall continue to operate as intended during and after the test. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended.

#### Performance criterion for Continuous phenomena applied to DECT Phone Receivers part

The primary functions shall be verified during each individual exposure in the test sequence.

Additionally for equipment containing analogue speech circuits the speech output signal level shall be at least 35 dB less than the previously recorded reference level. At the conclusion of

the test, the EUT shall operate as intended with no loss of user control functions or stored data, as declared by the manufacturer, and the communications link shall have been maintained. This shall be verified by checking the primary functions.

#### Performance criterion for charger

The apparatus shall continue to operate as intended during and after the test. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended.

### Criterion B

#### Performance criterion for Transient phenomena applied to DECT Phone Transceivers part

At the conclusion of each exposure the EUT shall operate with no user noticeable loss of the communications link. At the conclusion of the total test comprising the series of individual exposures the EUT shall operate as intended with no loss of user control functions or stored

data, as declared by the manufacturer, and the communications link shall have been maintained. Where the EUT is capable of transmission, tests shall be performed to ensure that unintentional transmission does not occur.

**Performance criterion for Transient Continuous phenomena applied to DECT Phone Receivers part**

At the conclusion of each exposure the EUT shall operate with no user noticeable loss of the communications link. At the conclusion of the total test comprising the series of individual exposures the EUT shall operate as intended with no loss of user control functions or stored data, as declared by the manufacturer, and the communications link shall have been maintained. This shall be verified by checking the primary functions.

**Performance criterion for charger**

The apparatus shall continue to operate as intended during and after the test. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended.

**Criterion C**

Temporary loss of function is allowed, provided the function is self-recoverable or can be restored by the operation of the controls.

**Immunity test configuration notes:**

For all kinds of test the Fixed Part was supplied with 230 V AC.

During the immunity tests with audio break through, the Telephone line was supplied with 60 V DC by a battery and the audio signal was decoupled by a feeding bridge (Signals for MRP (Mouth Reference Point)).

The Audio signals at the Portable part were measured by an acoustical monitoring system with an optical microphone. (Signals for ERP (Ear Reference Point)) The audio signals were measured with the help of an audio analyzer.

During the immunity tests with monitoring the BER (Bit Error Rate) FP (Fixed Part) was connected to a DECT communication Tester CMD 60, for measuring the BER.

During the immunity tests with monitoring the BER (Bit Error Rate) PP (Portable Part) was connected to a DECT communication Tester CMD 60, for measuring the BER.

During the other immunity tests a voice call was realized by using telephone private branch network. The call was monitored by the operator.

The volume setting of the Portable part was set to level 2 of 3, this setting level was given by the applicant.

During the other immunity tests a phone call was realized by using telephone private branch network. The call was monitored by the operator.

**Objective**

The following test report is prepared on behalf of *Xingtel Xiamen Group Co., Ltd.* in accordance with ETSI EN 301 489-1 V1.8.1 (2008-04) Plus Provisions of ETSI EN 301 489-6 V1.3.1 (2008-08), Electromagnetic compatibility and Radio spectrum Matters (ERM); ElectroMagnetic Compatibility (EMC) standard for radio equipment and services; Part 6: Specific conditions for Digital Enhanced Cordless Telecommunications (DECT) equipment.

The objective of the manufacturer is to determine compliance with ETSI EN 301 489-1 V1.8.1 (2008-04) Plus Provisions of ETSI EN 301 489-6 V1.3.1 (2008-08).

**Related Submittal(s)/Grant(s)**

No related submittal(s).

**Test Methodology**

All measurements contained in this report were conducted with ETSI EN 301 489-1 V1.8.1 (2008-04).

**Test Facility**

The Test site used by Bay Area Compliance Laboratories Corp.(Shenzhen) to collect test data is located on the 6/F, the 3rd Phase of WanLi Industrial Building, ShiHua Road, FuTian Free Trade Zone Shenzhen, Guangdong, China.

Test site at Bay Area Compliance Laboratories Corp. (Shenzhen) has been fully described in reports submitted to the Federal Communication Commission (FCC). The details of these reports have been found to be in compliance with the requirements of Section 2.948 of the FCC Rules on December 06, 2010. The facility also complies with the radiated and AC line conducted test site criteria set forth in ANSI C63.4-2009.

The Federal Communications Commission has the reports on file and is listed under FCC Registration No.: 382179. The test site has been approved by the FCC for public use and is listed in the FCC Public Access Link (PAL) database.

Additionally, Bay Area Compliance Laboratories Corp. (Shenzhen) is an ISO/IEC 17025 accredited laboratory, and is accredited by National Voluntary Laboratory Accredited Program (Lab Code 200707-0).



The current scope of accreditations can be found at <http://ts.nist.gov/Standards/scopes/2007070.htm>



## SYSTEM TEST CONFIGURATION

### Description of Test Configuration

The system was configured for testing in a typical fashion (as normally used by a typical user).

### Equipment Modifications

No modifications were made to the unit tested.

### Local Support Equipment List and Details

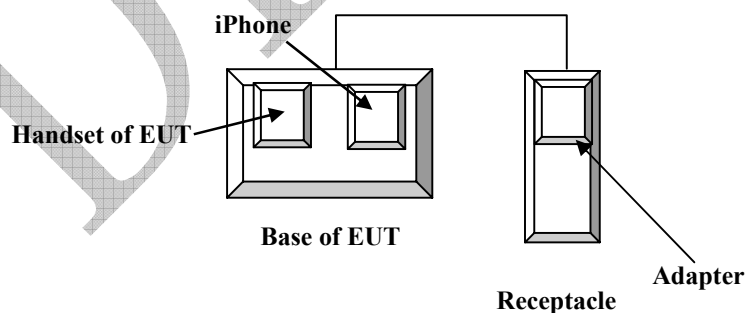
Manufacturer	Description	Model	Serial Number
Apple	iPhone 4	A1332	EMC380A
OneKe	Program-control Telephone Exchange	TC-108H	N/A
TIANNIAO	PHONE	TL2201	N/A

### External I/O Cable

Cable Description	Length (m)	From Port	To
Unshielded Detectable DC Power Cable	1.5	EUT	Adapter
Unshielded Detectable RJ11 Cable	2.0	EUT	Program-control Telephone Exchange

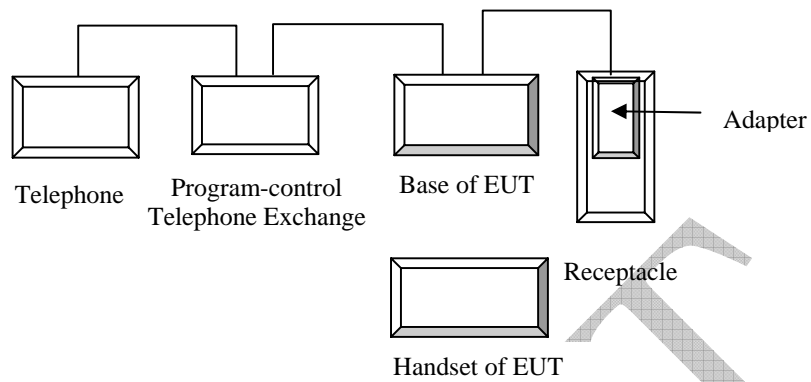
### Configuration of Test Setup

For charging mode:



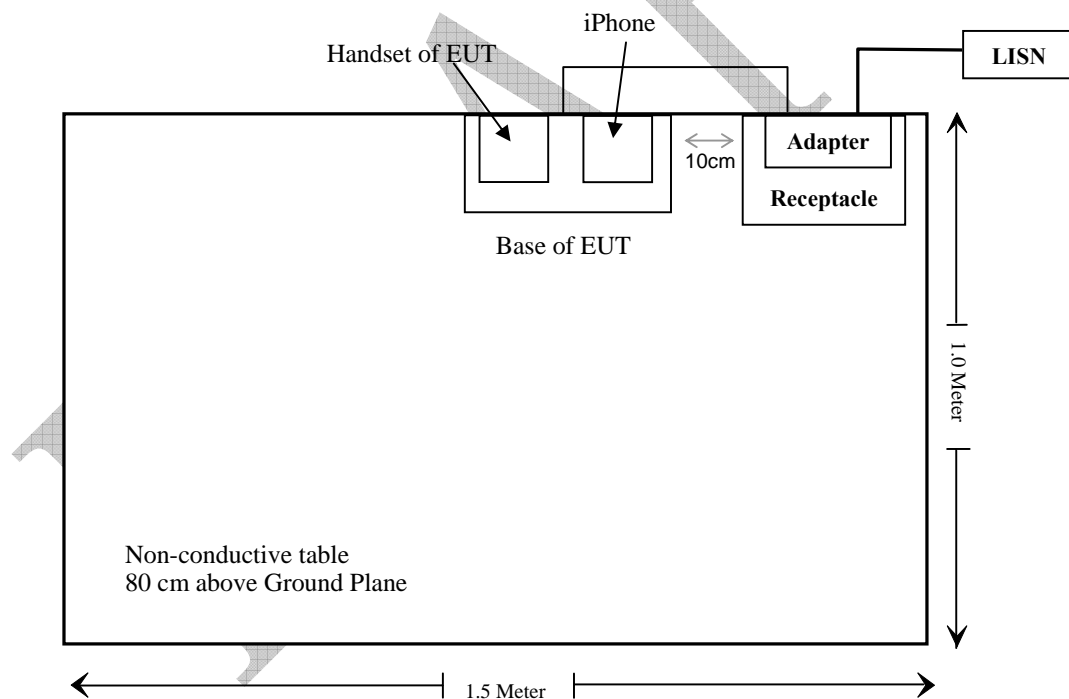


For talking mode:

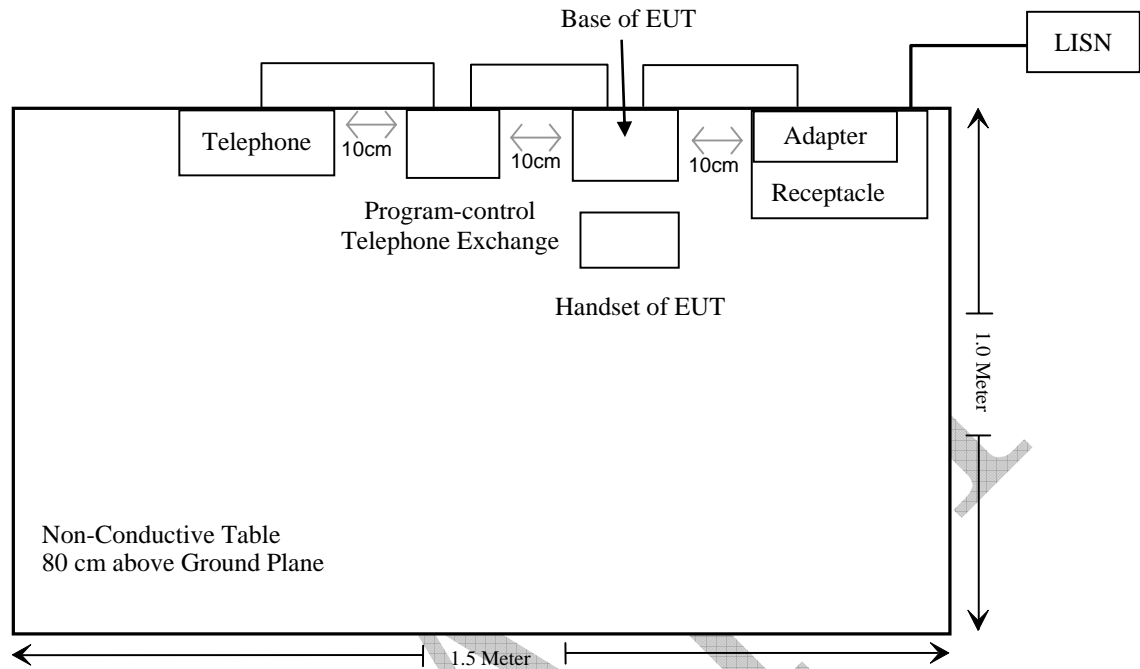


### Block Diagram of Test Setup

For charging mode:



For Talking mode:



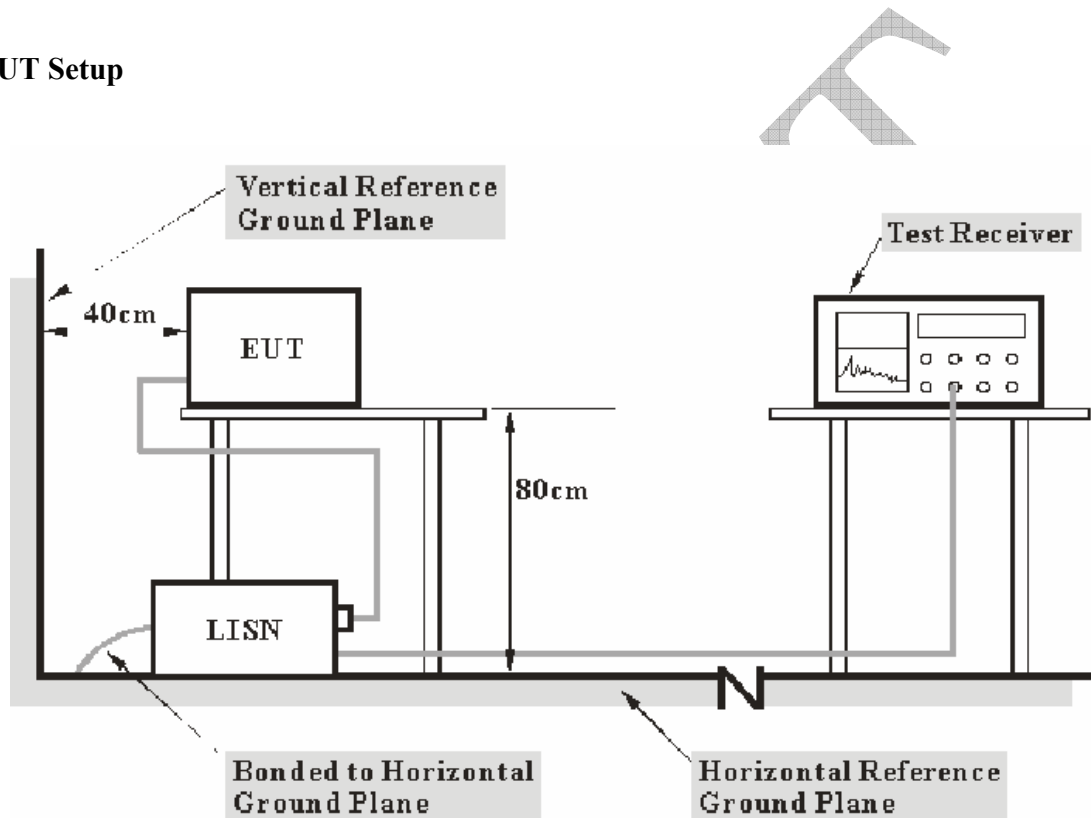
## SUMMARY OF TEST RESULTS

ETSI EN 301 489-6 V1.3.1 (2008-08)	Description of Test	Result
§7.1	Reference to clauses EN 301 489-1 §8.4 AC mains power input/output ports	Compliance
	Reference to clauses EN 301 489-1 §8.3 DC power input/output ports	N/A
	Reference to clauses EN 301 489-1 §8.2 Enclosure of ancillary equipment measured on a stand alone basis	Compliance
	Reference to clauses EN 301 489-1 §8.5 Harmonic current emissions (AC mains input port)	Compliance
	Reference to clauses EN 301 489-1 §8.6 Voltage fluctuations and flicker (AC mains input port)	Compliance
	Reference to clauses EN 301 489-1 §8.7 Telecommunication ports	N/A
§7.2	Reference to clauses EN 301 489-1 §9.2 Radio frequency electromagnetic field (80 MHz to 1 000 MHz and 1 400 MHz to 2 700 MHz)(EN 61000-4-3)	Compliance
	Reference to clauses EN 301 489-1 §9.3 Electrostatic discharge (EN 61000-4-2)	Compliance
	Reference to clauses EN 301 489-1 §9.4 Fast transients, common mode (EN 61000-4-4)	Compliance
	Reference to clauses EN 301 489-1 §9.5 Radio frequency, common mode (EN 61000-4-6)	Compliance
	Reference to clauses EN 301 489-1 §9.6 Transients and surges in the vehicular environment (ISO 7637-2)	N/A
	Reference to clauses EN 301 489-1 §9.8 Surges (EN 61000-4-5)	Compliance
	Reference to clauses EN 301 489-1 §9.7 Voltage dips and interruptions (EN 61000-4-11)	Compliance

**ETSI EN 301 489-6 V1.3.1 (2008-08) §7.1 - CONDUCTED EMISSIONS****Measurement Uncertainty**

All measurements involve certain levels of uncertainties, especially in field of EMC. The factors contributing to uncertainties are spectrum analyzer, cable loss, and LISN.

Based on CISPR 16-4-4, The Treatment of Uncertainty in EMC Measurements, the best estimate of the uncertainty of any conducted emissions measurement at Bay Area Compliance Laboratories Corp. (Shenzhen) is 2.4 dB.

**EUT Setup**

- Note:**
1. Support units were connected to second LISN.
  2. Both of LISNs (AMN) 80 cm from EUT and at the least 80 cm from other units and other metal planes support units.

The setup of EUT is according with per EN 301 489-1 measurement procedures. The specification used was with the EN 301 489-6 limits.

The external I/O cables were draped along the test table and formed a bundle 30 to 40 cm long in the middle.

The adapter was connected to AC 230V/50Hz power source.

## EMI Test Receiver Setup

The EMI test receiver was set to investigate the spectrum from 150 kHz to 30 MHz.

During the conducted emission test, the EMI test receiver was set with the following configurations:

<u>Frequency Range</u>	<u>IFBW</u>
150 kHz – 30 MHz	9 kHz

## Test Equipment List and Details

Manufacturer	Description	Model	Serial Number	Calibration Date	Calibration Due Date
Rohde & Schwarz	EMI Test Receiver	ESCS30	830245	2011-03-03	2012-03-02
Rohde & Schwarz	L.I.S.N.	ESH2-Z5	892107/021	2011-03-09	2012-03-08

\* **Statement of Traceability:** Bay Area Compliance Laboratories Corp. (Shenzhen) attests that all calibrations have been performed in accordance to NVLAP requirements, traceable to the NIST.

## Test Procedure

During the conducted emission test, the adapter was connected to the LISN.

Maximizing procedure was performed on the six (6) highest emissions of the EUT.

All data was recorded in the Quasi-peak and average detection mode.

## Test Results Summary

According to the recorded data in following table, the EUT complied with the ETSI EN 301 489-6, with the worst margin reading of:

**4.64 dB** at 0.810 MHz in the **Line** conducted mode for charging mode

## Test Data

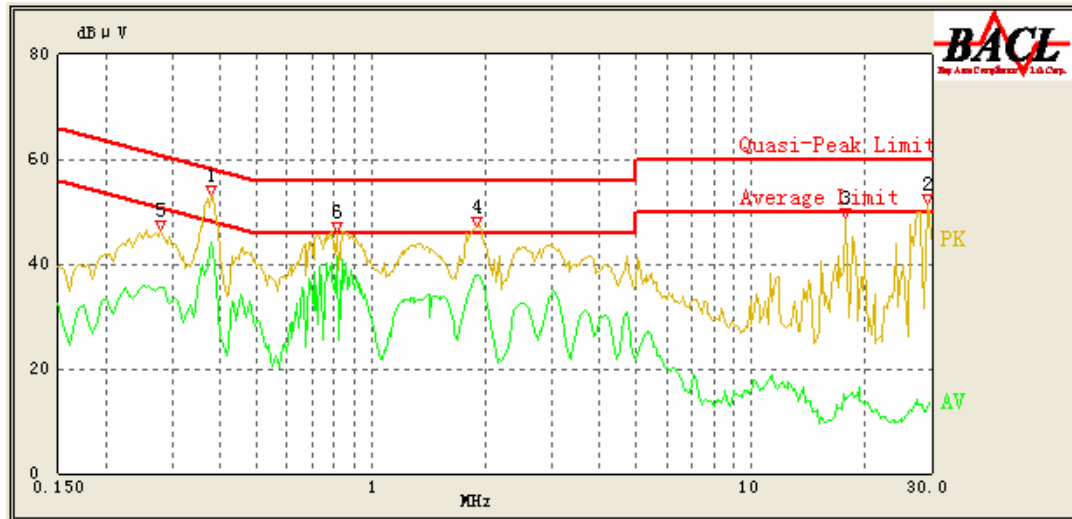
### Environmental Conditions

Temperature:	25 °C
Relative Humidity:	56 %
ATM Pressure:	100.0 kPa

*The testing was performed by Jimmy Xiao on 2011-11-28.*

Test Mode: Charging

AC 230V/50 Hz, Line



Frequency (MHz)	Corrected Amplitude (dBμV)	Correction Factor (dB)	Limit (dBμV)	Margin (dB)	Dedector (PK/QP/Ave.)
0.810	41.36	10.24	46.00	4.64	Ave.
0.380	44.23	10.23	49.43	5.20	Ave.
1.905	37.81	10.32	46.00	8.19	Ave.
0.380	50.50	10.23	59.43	8.93	QP
29.125	50.50	13.06	60.00	9.50	QP
0.810	44.86	10.24	56.00	11.14	QP
1.905	44.58	10.32	56.00	11.42	QP
0.280	35.66	10.23	52.29	16.63	Ave.
0.280	42.63	10.23	62.29	19.66	QP
17.695	14.11	11.49	50.00	35.89	Ave.
28.975	11.99	13.03	50.00	38.01	Ave.
17.795	15.56	11.49	60.00	44.44	QP

**AC 230V/50 Hz, Neutral:**

Frequency (MHz)	Corrected Amplitude (dBμV)	Correction Factor (dB)	Limit (dBμV)	Margin (dB)	Dedector (PK/QP/Ave.)
0.790	36.89	10.24	46.00	9.11	Ave.
0.370	49.54	10.23	59.71	10.17	QP
1.935	33.36	10.32	46.00	12.64	Ave.
1.935	42.57	10.32	56.00	13.43	QP
0.370	35.21	10.23	49.71	14.50	Ave.
0.790	41.49	10.24	56.00	14.51	QP
0.255	44.10	10.23	63.00	18.90	QP
4.290	35.78	10.54	56.00	20.22	QP
0.255	31.81	10.23	53.00	21.19	Ave.
4.285	23.66	10.54	46.00	22.34	Ave.
18.565	19.21	11.50	50.00	30.79	Ave.
18.415	24.83	11.50	60.00	35.17	QP

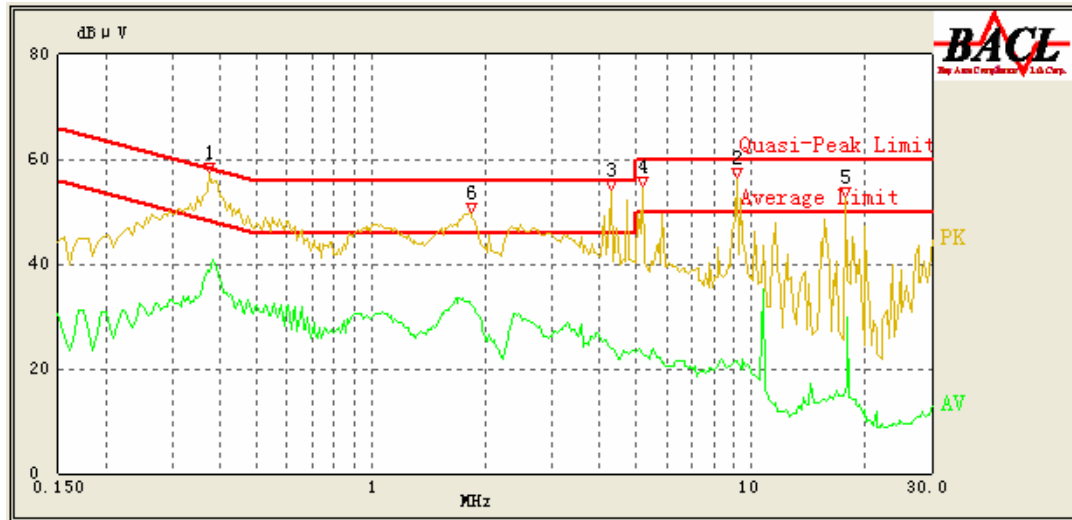


Test Mode: Talking

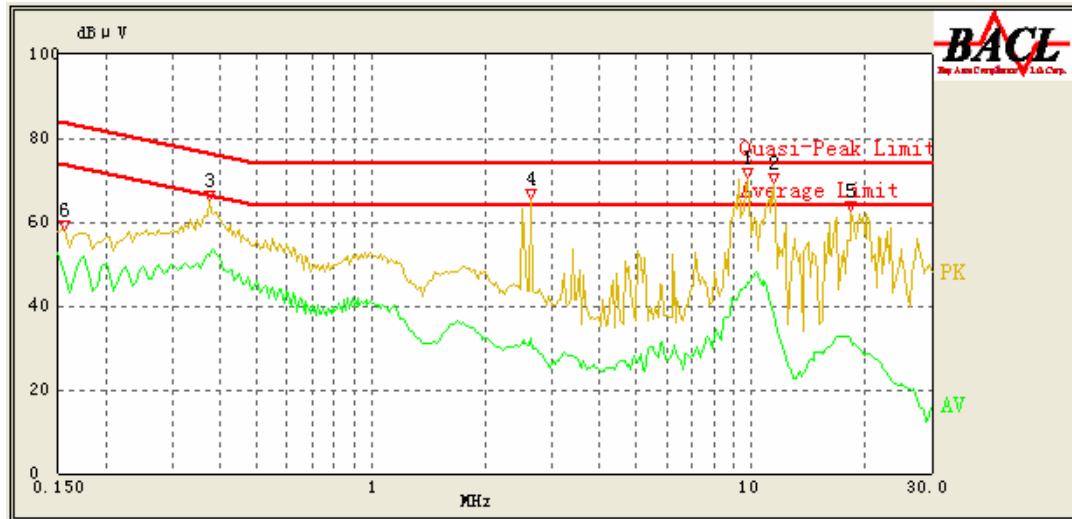
AC 230V/50 Hz, Line



Frequency (MHz)	Corrected Amplitude (dBμV)	Correction Factor (dB)	Limit (dBμV)	Margin (dB)	Dedector (PK/QP/Ave.)
0.375	42.05	10.23	49.57	7.52	Ave.
0.575	36.73	10.23	46.00	9.27	Ave.
1.790	35.76	10.31	46.00	10.24	Ave.
0.965	35.73	10.24	46.00	10.27	Ave.
0.375	48.34	10.23	59.57	11.23	QP
0.575	42.03	10.23	56.00	13.97	QP
1.795	41.68	10.31	56.00	14.32	QP
0.965	41.24	10.24	56.00	14.76	QP
8.685	20.67	10.87	50.00	29.33	Ave.
8.735	29.54	10.87	60.00	30.46	QP
19.120	13.84	11.51	50.00	36.16	Ave.
19.085	17.55	11.51	60.00	42.45	QP

**AC 230V/50 Hz, Neutral:**

Frequency (MHz)	Corrected Amplitude (dBμV)	Correction Factor (dB)	Limit (dBμV)	Margin (dB)	Dedector (PK/QP/Ave.)
0.375	51.73	10.23	59.57	7.84	QP
0.375	38.63	10.23	49.57	10.94	Ave.
1.830	44.21	10.31	56.00	11.79	QP
1.815	32.90	10.31	46.00	13.10	Ave.
4.305	34.58	10.54	56.00	21.42	QP
4.290	23.81	10.54	46.00	22.19	Ave.
5.200	35.49	10.61	60.00	24.51	QP
5.200	22.75	10.61	50.00	27.25	Ave.
9.215	31.77	10.90	60.00	28.23	QP
9.170	21.34	10.90	50.00	28.66	Ave.
17.895	16.71	11.49	50.00	33.29	Ave.
17.755	19.70	11.49	60.00	40.30	QP

**AC 230V/50 Hz, RJ11:**

Frequency (MHz)	Corrected Amplitude (dBμV)	Correction Factor (dB)	Limit (dBμV)	Margin (dB)	Dedector (PK/QP/Ave.)
0.375	51.83	10.23	67.57	15.74	Ave.
0.375	59.68	10.23	77.57	17.89	QP
9.760	45.46	10.94	64.00	18.54	Ave.
11.510	38.23	11.10	64.00	25.77	Ave.
0.155	47.66	10.23	73.86	26.20	Ave.
9.840	46.94	10.95	74.00	27.06	QP
0.155	53.53	10.23	83.86	30.33	QP
2.640	32.28	10.39	64.00	31.72	Ave.
18.580	30.68	11.50	64.00	33.32	Ave.
18.420	39.52	11.50	74.00	34.48	QP
11.540	38.94	11.11	74.00	35.06	QP
2.640	37.40	10.39	74.00	36.60	QP

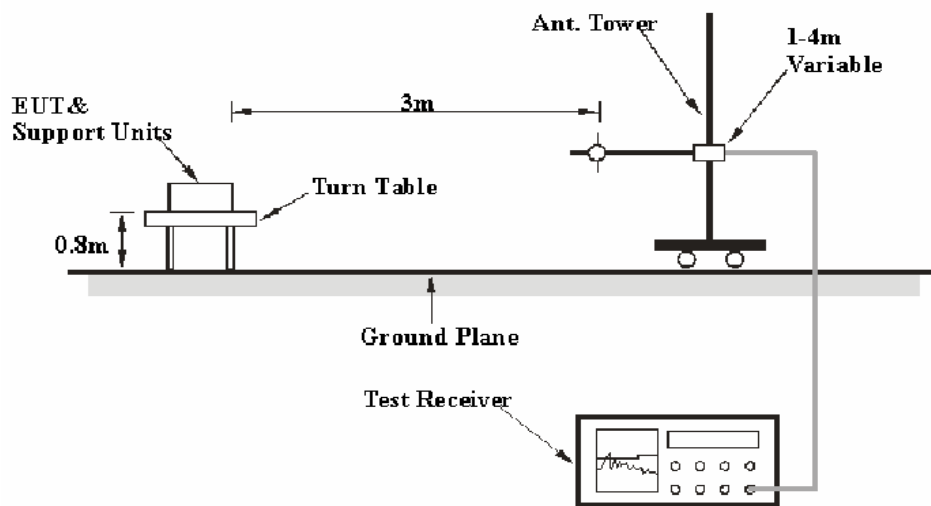
**ETSI EN 301 489-6 V1.3.1 (2008-08) §7.1 - RADIATED EMISSIONS****Measurement Uncertainty**

All measurements involve certain levels of uncertainties, especially in field of EMC. The factors contributing to uncertainties are spectrum analyzer, cable loss, antenna factor calibration, antenna directivity, antenna factor variation with height, antenna phase center variation, antenna factor frequency interpolation, measurement distance variation, site imperfections, mismatch (average), and system repeatability.

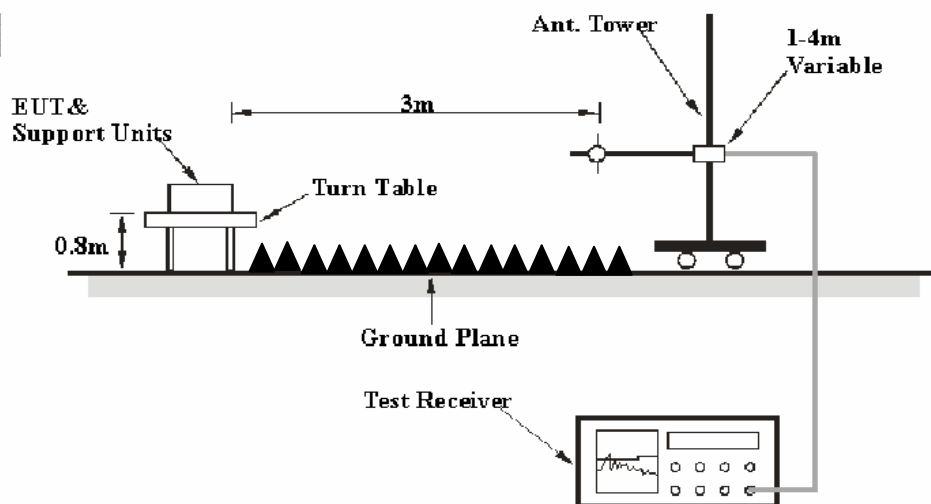
Based on CISPR 16-4-4, The Treatment of Uncertainty in EMC Measurements, the best estimate of the uncertainty of a radiation emissions measurement at Bay Area Compliance Laboratories Corp. (Shenzhen) is 4.0 dB.

**Test System Setup**

**Below 1 GHz:**



**Above 1 GHz:**



The radiated emission tests were performed in the 3 meters, using the setup accordance with the EN 301 489-1. The specification used was the EN 301 489-6.

The external I/O cables were draped along the test table and formed a bundle 30 to 40 cm long in the middle.

The adapters were connected to a 230 VAC/50 Hz power source.

### EMI Test Receiver Setup

The system was investigated from 30 MHz to 6 GHz.

During the radiated emission test, the EMI test receiver Setup was set with the following configurations:

<b><i>Frequency Range</i></b>	<b><i>RBW</i></b>	<b><i>Video B/W</i></b>	<b><i>Detector</i></b>
30MHz – 1000 MHz	100 kHz	300 kHz	QP
Above 1 GHz	1 MHz	3 MHz	PK
Above 1 GHz	1 MHz	3 MHz	Ave

### Test Equipment List and Details

<b>Manufacturer</b>	<b>Description</b>	<b>Model</b>	<b>Serial Number</b>	<b>Calibration Date</b>	<b>Calibration Due Date</b>
HP	Amplifier	HP8447E	1937A01046	2011-08-02	2012-08-02
Rohde & Schwarz	EMI Test Receiver	ESCI	100035	2011-11-11	2012-11-10
Sunol Sciences	Broadband Antenna	JB1	A040904-1	2011-07-05	2012-07-04
Sunol Sciences	Horn Antenna	DRH-118	A052604	2011-05-05	2012-05-04
Mini-circuits	Pre-Amplifier	ZVA-213+	T-E27H	2011-03-08	2012-03-07
Rohde & Schwarz	Signal Analyzer	FSIQ 26	609358	2011-07-08	2012-07-07

\* **Statement of Traceability:** Bay Area Compliance Laboratories Corp. (Shenzhen) attests that all calibrations have been performed in accordance to NVLAP requirements, traceable to the NIST.

### Test Procedure

For the radiated emissions test, the adapter was connected to the AC floor outlet.

Maximizing procedure was performed on the highest emissions to ensure that the EUT complied with all installation combinations.

The data was recorded in the Quasi-peak detection mode for below 1 GHz. Peak and average detection mode above 1 GHz.

### Corrected Amplitude & Margin Calculation

The Corrected Amplitude is calculated by adding the Antenna Factor and Cable Loss, and subtracting the Amplifier Gain from the Meter Reading. The basic equation is as follows:

$$\text{Corrected Amplitude} = \text{Meter Reading} + \text{Antenna Factor} + \text{Cable Loss} - \text{Amplifier Gain}$$

The “**Margin**” column of the following data tables indicates the degree of compliance with the applicable limit. For example, a margin of 7dB means the emission is 7dB below the limit for Class B. The equation for margin calculation is as follows:

$$\text{Margin} = \text{Limit} - \text{Corrected Amplitude}$$

### Test Results Summary

According to the recorded data in following table, the EUT complied with the ETSI EN 301 489-1, with the worst margin reading of:

**8.97 dB at 3785.57 MHz in the Horizontal polarization for charging mode**

### Test Data

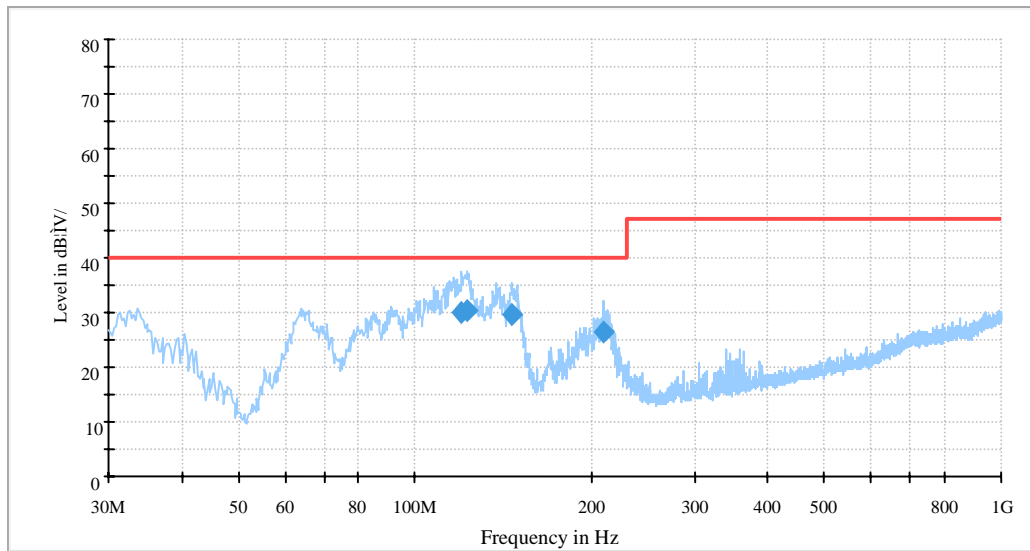
#### Environmental Conditions

<b>Temperature:</b>	25 °C
<b>Relative Humidity:</b>	56 %
<b>ATM Pressure:</b>	100.0 kPa

*The testing was performed by Jimmy Xiao on 2011-11-18.*

**Below 1 GHz:***Test Mode: Charging*

Auto Test



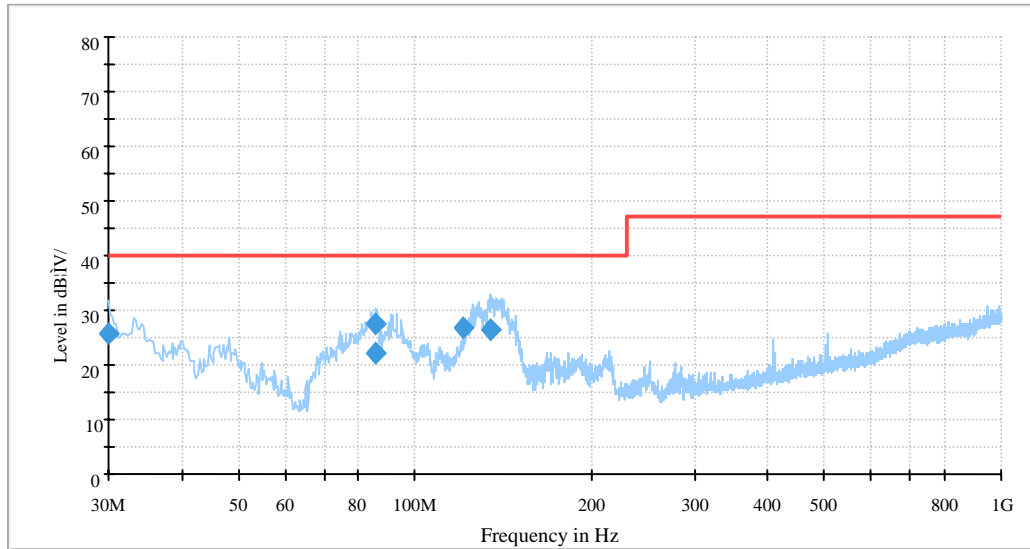
Frequency (MHz)	Corrected Amplitude (dBµV/m)	Antenna Height (cm)	Antenna Polarity (H/V)	Turntable Position (degree)	Corrected Factor (dB)	Limit (dBµV/m)	Margin (dB)
122.835250	30.3	123.0	V	304.0	-12.3	40.0	9.7
119.940750	29.9	129.0	V	304.0	-12.3	40.0	10.1
146.514000	29.6	144.0	V	332.0	-13.7	40.0	10.4
209.846250	26.4	100.0	V	304.0	-14.2	40.0	13.6

Note: the data which below 20 dB limit was not recorded.



Test Mode: Talking

Auto Test (EN301489)



Frequency (MHz)	Corrected Amplitude (dBµV/m)	Antenna Height (cm)	Antenna Polarity (H/V)	Turntable Position (degree)	Corrected Factor (dB)	Limit (dBµV/m)	Margin (dB)
85.940250	27.5	393.0	H	2.0	-17.8	40.0	12.5
120.832750	26.7	100.0	V	296.0	-12.3	40.0	13.3
134.551750	26.5	100.0	V	294.0	-12.8	40.0	13.5
30.064375	25.6	114.0	V	212.0	-5.4	40.0	14.4
85.594500	22.2	400.0	H	182.0	-17.8	40.0	17.8

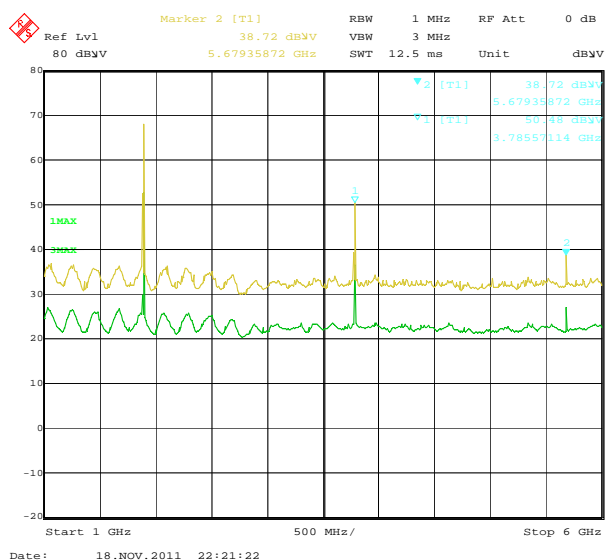
Note: the data which below 20 dB limit was not recorded.

**Above 1 GHz:***Test Mode: Charging*

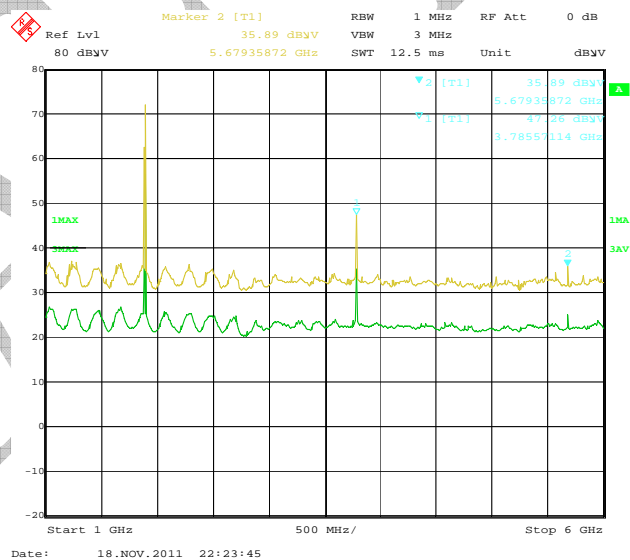
Frequency (MHz)	Meter Reading (dBμV)	Detector (PK/QP/Ave)	Direction (Degree)	Height (m)	Polar (H/V)	Antenna Factor (dB)	Cable Loss (dB)	Amplifier (dB)	Corrected Amplitude (dBμV/m)	EN 301 489-1	
										Limit (dBμV/m)	Margin (dB)
3785.57	36.44	Ave.	358	1.3	V	32.10	3.70	27.66	44.58	54	9.42
3785.57	38.85	Ave.	183	1.2	H	32.10	3.70	27.66	46.99	54	7.01
3785.57	47.26	PK	358	1.3	V	32.10	3.70	27.66	55.40	74	18.60
3785.57	50.48	PK	183	1.2	H	32.10	3.70	27.66	58.62	74	15.38

Please refer to the following plots for prescan:

Horizontal: 1-6 GHz



Vertical: 1-6 GHz

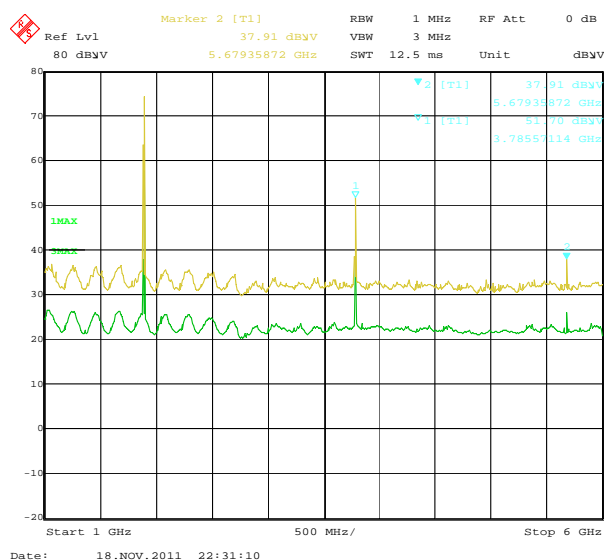


Test Mode: Talking

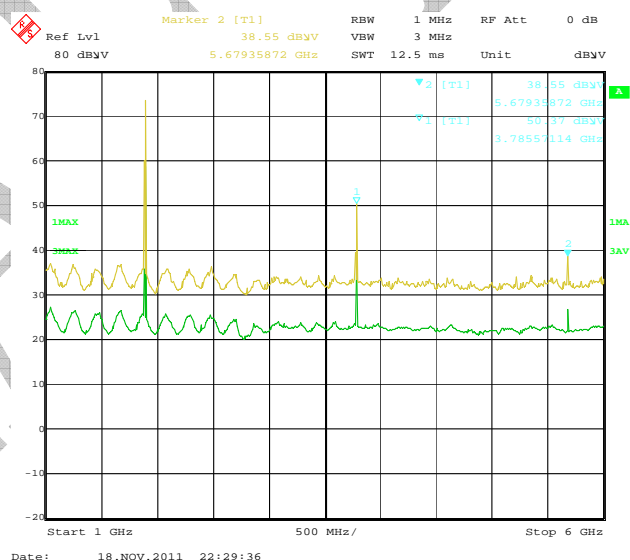
Frequency (MHz)	Meter Reading (dBμV)	Detector (PK/QP/Ave)	Direction (Degree)	Height (m)	Polar (H/V)	Antenna Factor (dB)	Cable Loss (dB)	Amplifier (dB)	Corrected Amplitude (dBμV/m)	EN 301 489-1	
										Limit (dBμV/m)	Margin (dB)
3785.57	36.89	Ave.	150	2.1	H	32.10	3.70	27.66	45.03	54	8.97
3785.57	35.42	Ave.	230	1.8	V	32.10	3.70	27.66	43.56	54	10.44
3785.57	51.70	PK	150	2.1	H	32.10	3.70	27.66	59.84	74	14.16
3785.57	50.37	PK	230	1.8	V	32.10	3.70	27.66	58.51	74	15.49

Please refer to the following plots for prescan:

Horizontal: 1-6 GHz



Vertical: 1-6 GHz



## **ETSI EN 301 489-6 V1.3.1 (2008-08) §7.1 - HARMONIC CURRENT EMISSIONS**

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According to EN 61000-3-2:2006 + A1:2009 + A2:2009 section 7: Equipment with a rated power of 75 W or less, other than lighting equipment, are out included in this standard.

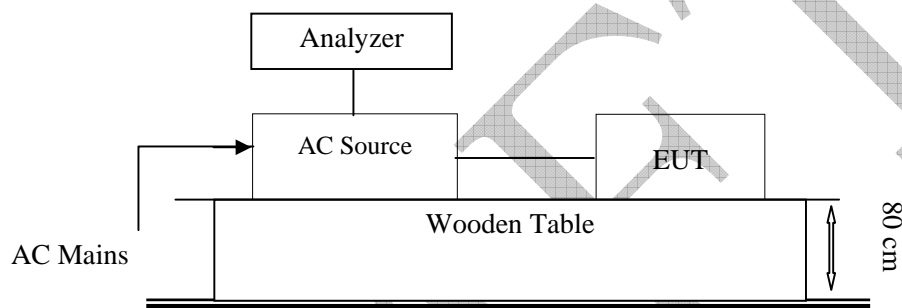
DRAFT

## ETSI EN 301 489-6 V1.3.1 (2008-08) §7.1 - VOLTAGE FLUCTUATION AND FLICKER

### Test Equipment

Manufacturer	Description	Model	Serial Number	Calibration Date	Calibration Due Date
EM Test	Harmonic/Flicker Analyzer	DPA 500N	V0939105176	2011-11-11	2012-11-10
EM Test	AC Source	ACS500	1101-02	2011-03-25	2012-03-24

### Test System Setup



### Test Standard

EN 61000-3-3: 2008

### Test Data and Setup Photo

Date of test:	20:27 27 Nov. 2011
Tester:	Jimmy Xiao
Standard used:	EN 61000-3-3 Flicker
Short time (Pst):	10 min
Observation time:	12 min (12 Flicker measurement)
Flickermeter:	230V / 50Hz
Customer:	Xingtai Xiamen Group Co., Ltd.
E. U. T.:	iPhone Complimate
Model:	i-700
Test mode:	Charging & Talking

## Maximum Flicker results

	EUT values	Limit	Result
Pst	0.028	1.00	PASS
Plt	0.028	0.65	PASS
dc [%]	0.015	3.30	PASS
dmax [%]	0.194	4.00	PASS
dt [s]	0.000	0.50	PASS

Charging mode



Talking mode

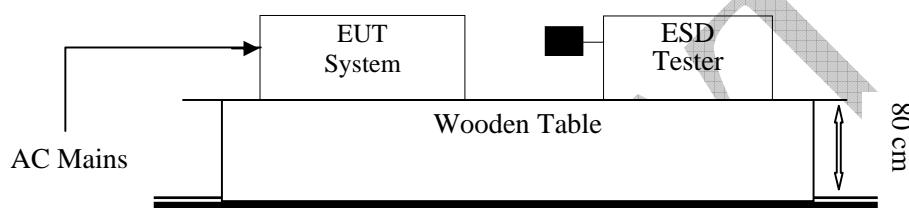


Test Setup Photos



**ETSI EN 301 489-6 V1.3.1 (2008-08) §7.2 - ELECTROSTATIC DISCHARGE****Test Equipment**

Manufacturer	Description	Model	Serial Number	Calibration Date	Calibration Due Date
EM Test	ESD Tester	Dito	302105	2011-10-27	2012-10-26

**Test System Setup**

Remark: ■ is the tip of the electrode

EN 61000-4-2 specifies that a tabletop EUT shall be placed on a non-conducting table which is 80 centimeters above a ground reference plane and that floor mounted equipment shall be placed on a insulating support approximately 10 centimeters above a ground plane. During the tests, the EUT is positioned over a ground reference plane in conformance with this requirement.

For tabletop equipment, a 1.5 by 1.0-meter metal sheet (HCP) is placed on the table and connected to the ground plane via a metal strap with two 470 k Ohms resistors in series. The EUT and attached cables are isolated from this metal sheet by 0.5-millimeter thick insulating material. A Vertical Coupling Plane (VCP) grounded on the ground plane through the same configuration as in the HCP is used.

**Test Standard**

ETSI EN 301 489-1 V1.8.1 / EN 61000-4-2:2009

Test Level 3 for Air Discharge at  $\pm 8$  kV

Test Level 2 for Contact Discharge at  $\pm 4$  kV

**Test Level**

Level	Test Voltage Contact Discharge ( $\pm$ kV)	Test Voltage Air Discharge ( $\pm$ kV)
1.	2	2
2.	4	4
3.	6	8
4.	8	15
X.	Special	Special

**Performance criterion: B**

## Test Procedure

### Air Discharge:

This test is done on a non-conductive surface. The round discharge tip of the discharge electrode shall be approached as fast as possible to touch the EUT. After each discharge, the discharge electrode shall be removed from the EUT. The generator is then re-triggered for a new single discharge and repeated 10 times for each pre-selected test point. This procedure shall be repeated until all the air discharge completed.

### Contact Discharge:

All the procedure shall be same as Section 8.3.1 of EN 61000-4-2, except that the tip of the discharge electrode shall touch the EUT before the discharge switch is operated.

### Indirect discharge for horizontal coupling plane

At least 20 single discharges shall be applied to the horizontal coupling plane, at points on each side of the EUT. The discharge electrode positions vertically at a distance of 0.1m from the EUT and with the discharge electrode touching the coupling plane.

### Indirect discharge for vertical coupling plane

At least 20 single discharges shall be applied to the center of one vertical edge of the coupling plane. The coupling plane, of dimensions 0.5m X 0.5m, is placed parallel to, and positioned at a distance of 0.1m from the EUT. Discharges shall be applied to the coupling plane, with this plane in sufficient different positions that the four faces of the EUT are completely illuminated.

## Test Data and Setup Photo

### Environmental Conditions

Temperature:	25 °C
Relative Humidity:	56 %
ATM Pressure:	100.0 kPa

*The testing was performed by Jimmy Xiao on 2011-11-28.*

Test Mode: Charging

**Table 1: Electrostatic Discharge Immunity (Air Discharge)**

EN 61000-4-2 Test Points Location	Test Levels							
	-2 kV	+2 kV	-4 kV	+4 kV	-8 kV	+8 kV	-15 kV	+15 kV
Insulating surface (10 points)	A	A	A	A	A	A	/	/
Slot (8 points)	A	A	A	A	A	A	/	/
Apertures (6 Points)	A	A	A	A	A	A	/	/
DC Jack (1 point)	A	A	A	A	A	A	/	/
RJ11 port (1 point)	A	A	A	A	A	A	/	/
Buttons slots (20 points)	A	A	A	A	A	A	/	/

**Table 2: Electrostatic Discharge Immunity (Direct Contact)**

EN 61000-4-2 Test Points Location	Test Levels							
	-2 kV	+2 kV	-4 kV	+4 kV	-6 kV	+6 kV	-8 kV	+8 kV
/	/	/	/	/	/	/	/	/
/	/	/	/	/	/	/	/	/

**Table 3: Electrostatic Discharge Immunity (Indirect Contact HCP)**

EN 61000-4-2 Test Points Location	Test Levels							
	-2 kV	+2 kV	-4 kV	+4 kV	-6 kV	+6 kV	-8 kV	+8 kV
Front Side	A	A	A	A	/	/	/	/
Back Side	A	A	A	A	/	/	/	/
Left Side	A	A	A	A	/	/	/	/
Right Side	A	A	A	A	/	/	/	/

**Table 4: Electrostatic Discharge Immunity (Indirect Contact VCP)**

EN 61000-4-2 Test Points Location	Test Levels							
	-2 kV	+2 kV	-4 kV	+4 kV	-6 kV	+6 kV	-8 kV	+8 kV
Front Side	A	A	A	A	/	/	/	/
Back Side	A	A	A	A	/	/	/	/
Left Side	A	A	A	A	/	/	/	/
Right Side	A	A	A	A	/	/	/	/

Test Mode: Talking

**Table 1: Electrostatic Discharge Immunity (Air Discharge)**

EN 61000-4-2 Test Points Location	Test Levels							
	-2 kV	+2 kV	-4 kV	+4 kV	-8 kV	+8 kV	-15 kV	+15 kV
BASE								
Insulating surface (10 points)	A	A	A	A	A	A	/	/
Slot (8 points)	A	A	A	A	A	A	/	/
Apertures (6 points)	A	A	A	A	A	A	/	/
DC Jack (1 point)	A	A	A	A	A	A	/	/
RJ11 port (1 point)	A	A	A	A	A	A	/	/
Buttons slots (2 points)	A	A	A	A	A	A	/	/
HANDSET								
Insulating surface (6 points)	A	A	A	A	A	A		
Slots (6 points)	A	A	A	A	A	A		
Apertures(1 points)	A	A	A	A	A	A		
LCD screen(4 points)	A	A	A	A	A	A		
Microphone port(1 point)	A	A	A	A	A	A		
Headphone( 2 points)	A	A	A	A	A	A		
Speaker(4 points)	A	A	A	A	A	A		
Button slots (40points)	A	A	A	A	A	A		

**Table 2: Electrostatic Discharge Immunity (Direct Contact)**

EN 61000-4-2 Test Points Location	Test Levels							
	-2 kV	+2 kV	-4 kV	+4 kV	-6 kV	+6 kV	-8 kV	+8 kV
i-phone charging connector -base (2 points)	A	A	A	A	/	/	/	/
Charging connector-handset (2 points)	A	A	A	A	/	/	/	/

**Table 3: Electrostatic Discharge Immunity (Indirect Contact HCP)**

EN 61000-4-2 Test Points Location	Test Levels							
	-2 kV	+2 kV	-4 kV	+4 kV	-6 kV	+6 kV	-8 kV	+8 kV
Front Side	A	A	A	A	/	/	/	/
Back Side	A	A	A	A	/	/	/	/
Left Side	A	A	A	A	/	/	/	/
Right Side	A	A	A	A	/	/	/	/

**Table 4: Electrostatic Discharge Immunity (Indirect Contact VCP)**

EN 61000-4-2 Test Points Location	Test Levels							
	-2 kV	+2 kV	-4 kV	+4 kV	-6 kV	+6 kV	-8 kV	+8 kV
Front Side	A	A	A	A	/	/	/	/
Back Side	A	A	A	A	/	/	/	/
Left Side	A	A	A	A	/	/	/	/
Right Side	A	A	A	A	/	/	/	/

**Charging mode:**

**Air Discharge**



**Indirect Contact**



**Talking mode:**

**Air Discharge**



**Indirect Contact**



**Test Setup photos**



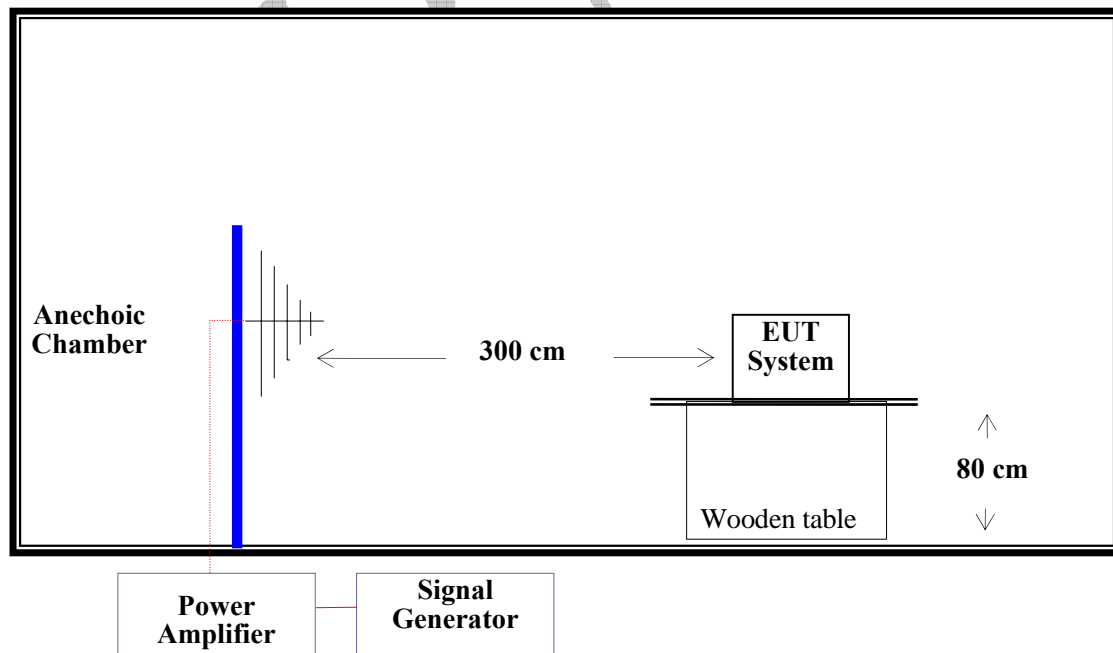
## ETSI EN 301 489-6 V1.3.1 (2008-08) §7.2 - RF ELECTROMAGNETIC FIELD (80 to 1000 MHz, 1400 to 2700 MHz)

### Test Equipment

Manufacturer	Description	Model	Serial Number	Calibration Date	Calibration Due Date
Amplifier Research	Amplifier Input/Output	200W1000/M2	15893	2011-01-14	2012-01-13
Amplifier Research	Field Meter	FM5004	302149	2011-03-26	2012-03-25
Amplifier Research	Sensor	FP5000	301825	2011-02-22	2012-02-21
HP	Signal Generator	8648C	3426A01345	2011-01-29	2012-01-28
Amplifier Research	Biconilog Antenna	AT1080	301902	2011-08-25	2012-08-24
HP	Synthesized Sweeper	8341B	2624A00116	2011-03-03	2012-03-02
Sunol Sciences	Horn Antenna	DRH-118	A052604	2011-05-05	2012-05-04
Brüel & Kjær	Measuring Amplifier	2610	SA0252	2011-05-30	2012-05-29
Brüel & Kjær	Artificial Head	4602B	2174439	2011-09-18	2012-09-17
Brüel & Kjær	Microphone Standard	2669	2159984	2011-09-18	2012-09-17
Brüel & Kjær	Ear Simulator	4185	2190351	2011-09-18	2012-09-17
LISTEN	Power Supply	Sound Connect	1199PS165	2011-09-18	2012-09-17
BK Precision	Sound Level meter	735	7350087309110025	2011-06-09	2012-06-08

\* **Statement of Traceability:** Bay Area Compliance Laboratories Corp. (Shenzhen) attests that all calibrations have been performed in accordance to NVLAP requirements, traceable to the NIST.

### Test System Setup



**Test Standard**

ETSI EN 301 489-1 V1.8.1 / EN 61000-4-3: 2006

Test Level 2 at 3V / m

Test Levels and Performance Criterion

**Test Level**

Level	Field Strength (V/m)
1.	1
2.	3
3.	10
X.	Special

**Performance Criterion: A\*** (\*Note: “A” stand for, the speech output signal level shall be at least 35 dB less than the reference level recorded before the start of the test. This shall be verified by the procedure in EN 301 489-6 V1.3.1 clause 5.3.2.)

**Test Procedure**

The EUT and its simulators are placed on a turn table which is 0.8 meter above the ground. The EUT is set 3 meters away from the transmitting antenna which is mounted on an antenna tower. Both horizontal and vertical polarizations of the antenna are set on test. Each of the four sides of EUT must be faced this transmitting antenna and measured individually.

In order to judge the EUT performance, an artificial ear and sound level meter are used to monitor the sound pressure level.

All the scanning conditions are as follows:

Condition of Test	Remarks
1. Field Strength	3 V/m (Test Level 2)
2. Radiated Signal	Modulated
3. Scanning Frequency	80 - 1000 MHz and 1400-2700MHz
4. Sweeping time of radiated	0.0015 decade/s
5. Dwell Time	1 Sec.

## Test Data and Setup Photo

### Environmental Conditions

Temperature:	25 °C
Relative Humidity:	56 %
ATM Pressure:	100.0 kPa

The testing was performed by Jimmy Xiao on 2011-11-28.

Test Mode: Charging & Talking

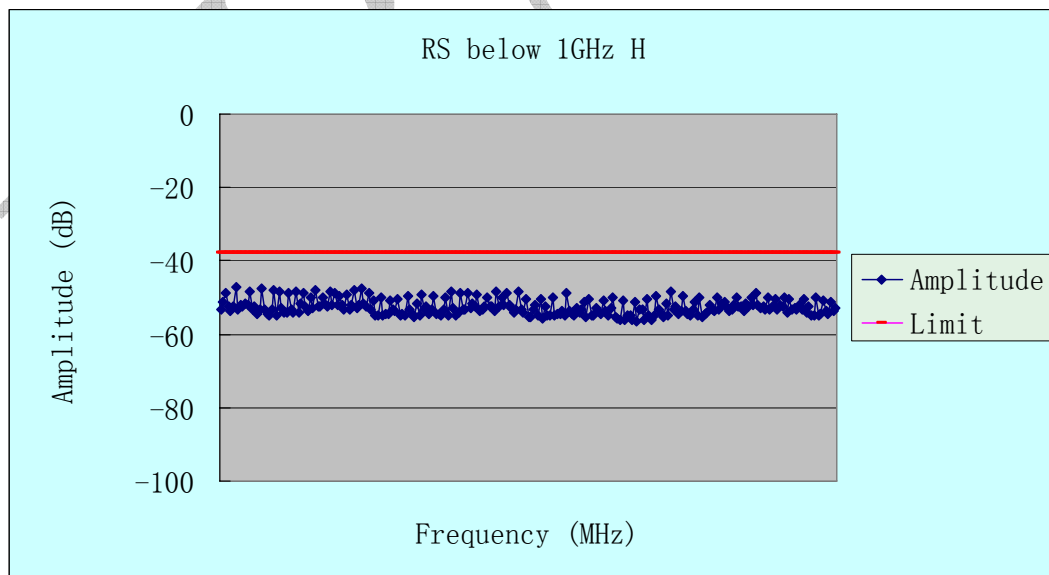
Frequency Range (MHz)	Front Side (3V/m)		Rear Side (3 V/m)		Left Side (3 V/m)		Right Side (3 V/m)	
	VERT	HORI	VERT	HORI	VERT	HORI	VERT	HORI
80-1000	A	A	A	A	A	A	A	A
1400-2700	A	A	A	A	A	A	A	A

Talking mode data as below:

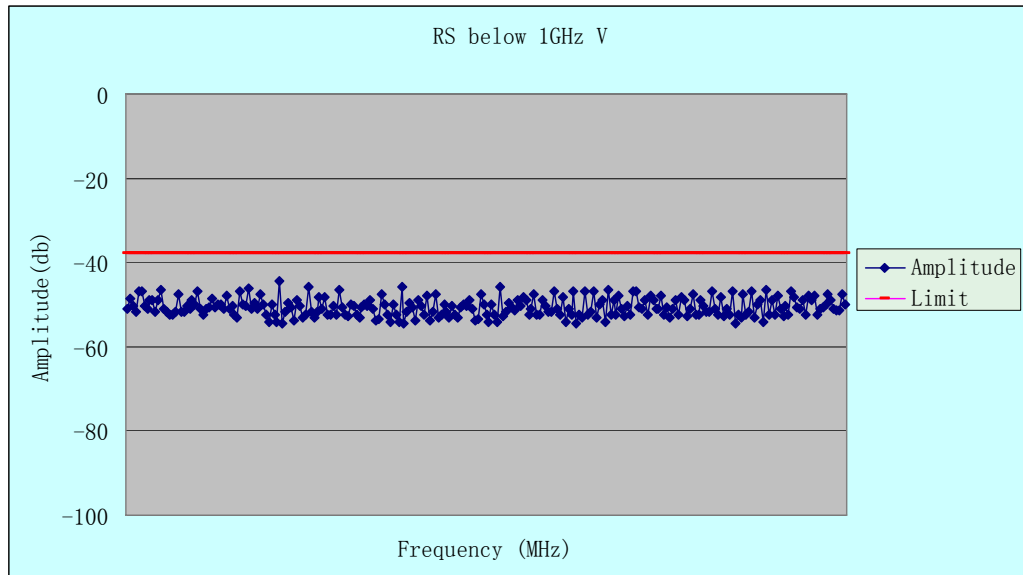
SPL(worst case) for test result as follows:

The reference level is -3 dB, be equivalent to (0 dBPa at 1 kHz, applied to the ear reference point in the receive path).The plots for worst case as follows:

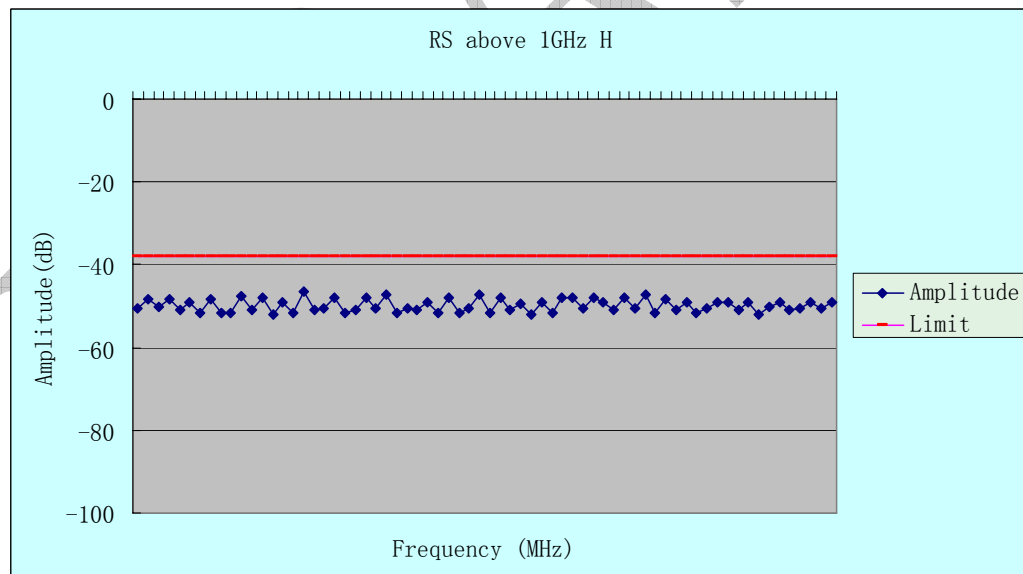
### RS-Horizontal (80 MHz-1000 MHz)

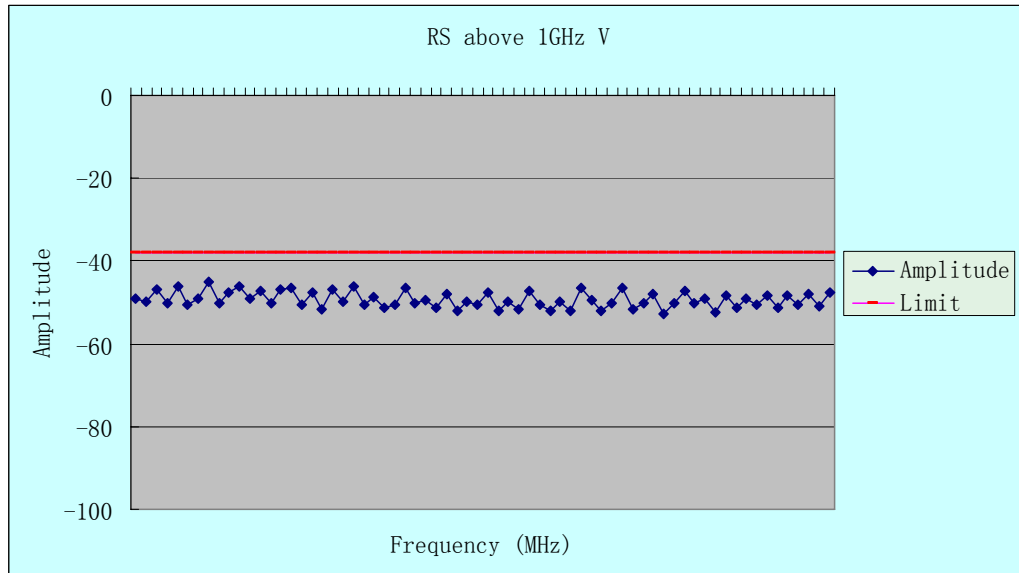


### RS-Vertical (80 MHz-1000 MHz)

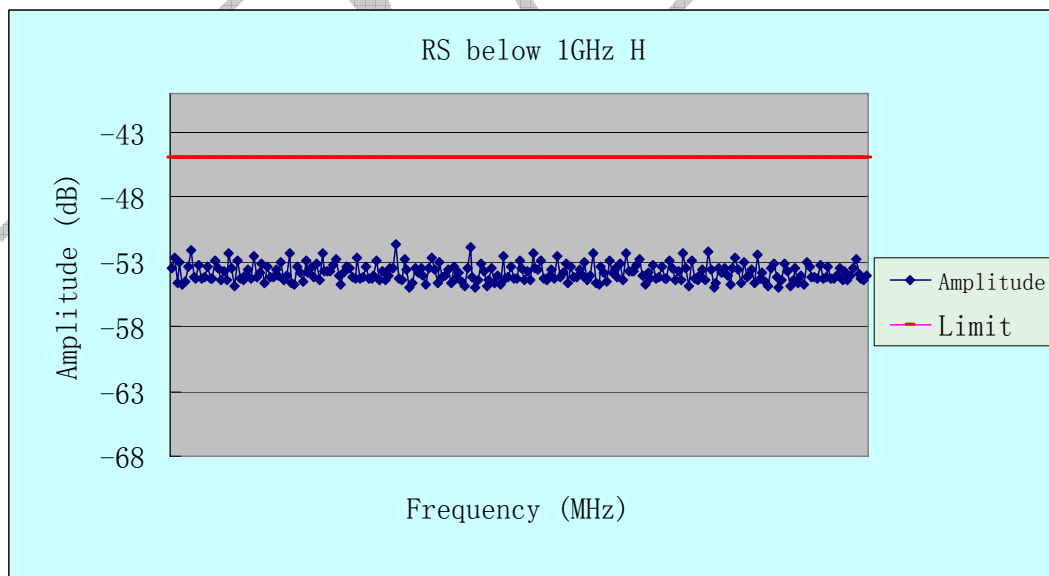


### RS-Horizontal (1400 MHz-2700 MHz)

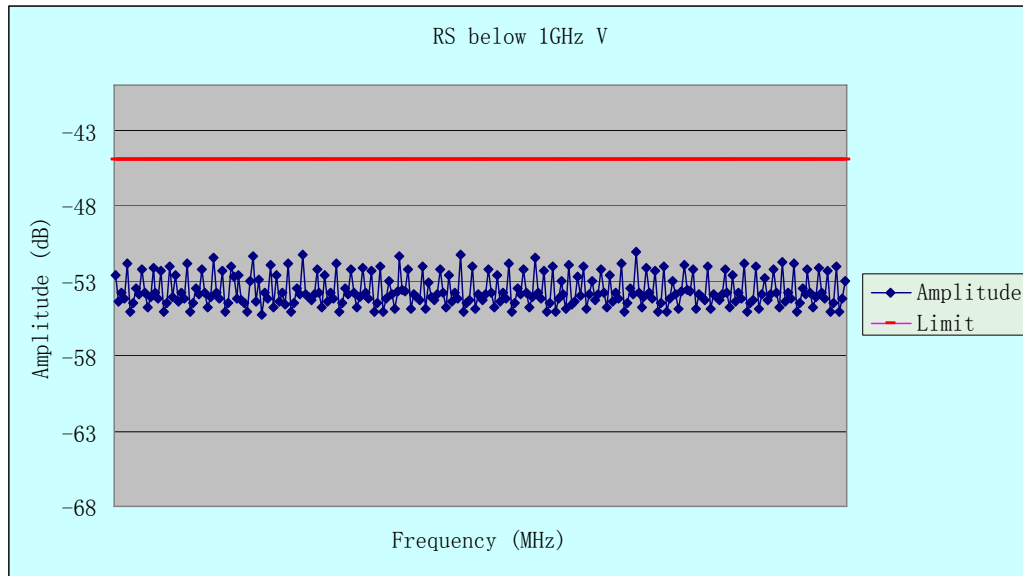


**RS-Vertical (1400 MHz-2700 MHz)**

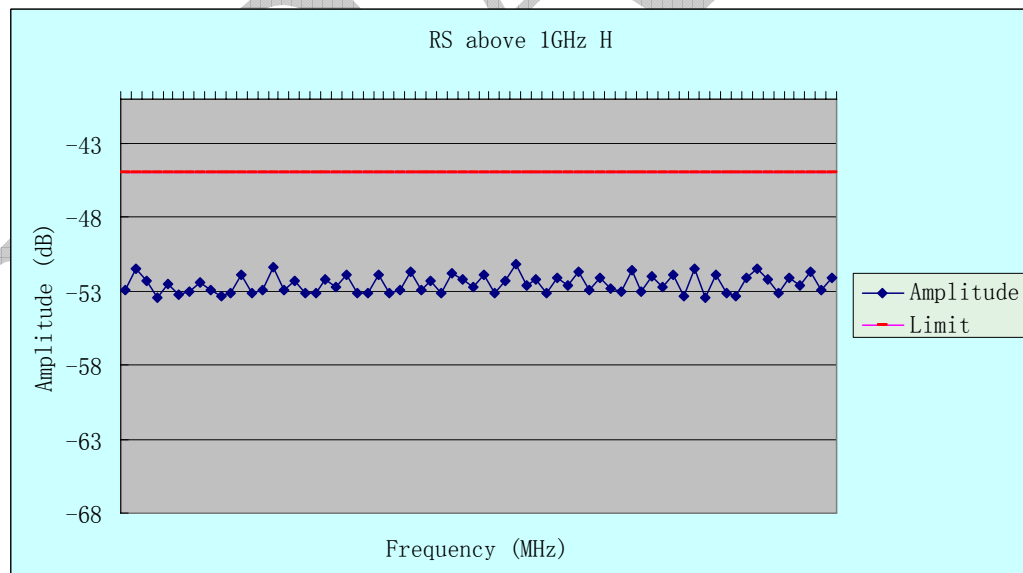
The reference level is -9dB, be equivalent to (-5 dBPa at 1 kHz applied to the mouth reference point).  
The plots for worst case as follows:

**RS-Horizontal (80 MHz-1000 MHz)**

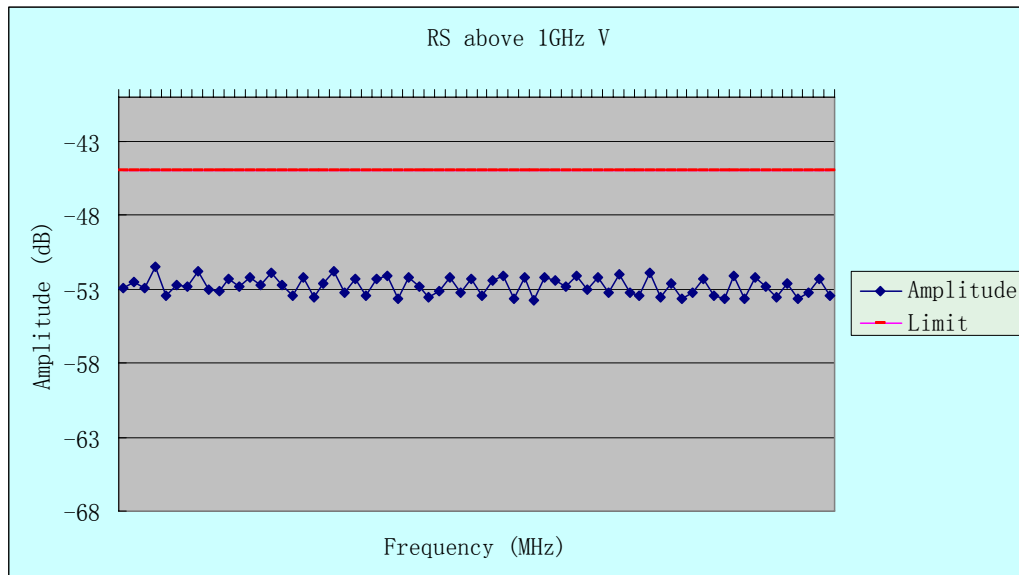
### RS-Vertical (80 MHz-1000 MHz)



### RS-Horizontal (1400 MHz-2700 MHz)



**RS-Vertical (1400 MHz-2700 MHz)**



### Charging mode



### Talking mode





**Base: TBR6 (BER)**



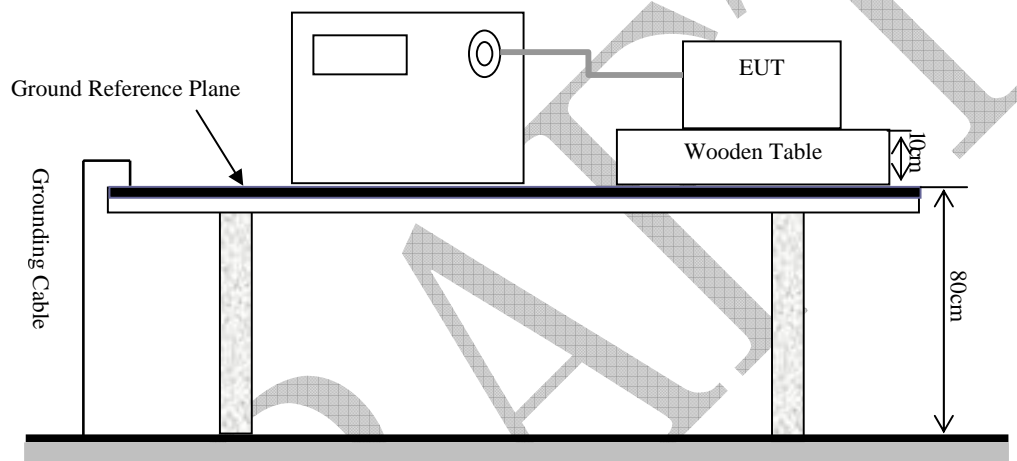
**Test Setup photos**

## ETSI EN 301 489-6 V1.3.1 (2008-08) §7.2 - FAST TRANSIENT IMMUNITY COMMON MODE

### Test Equipment

Manufacturer	Description	Model	Serial Number	Calibration Date	Calibration Due Date
EM Test	Ultra Compact Generator	UCS500-N5	V0939105172	2011-07-04	2012-07-03
EM Test	Auto-transformer	MV2616	V0939105173	2011-07-04	2012-07-03

### Test System Setup



### Test Standard

ETSI EN 301 489-1 V1.8.1/EN 61000-4-4: 2004

Test level 2 at 1 kV for AC main port

Test level 2 at 0.5 kV for signal port

### Test Level

Open Circuit Output Test Voltage $\pm 10\%$		
Level	On Power Supply Lines	On I/O (Input/Output) Signal data and control lines
1	0.5 kV	0.25 kV
2	1 kV	0.5 kV
3	2 kV	1 kV
4	4 kV	2 kV
X	Special	Special

### Performance Criterion: B

## Test Procedure

The EUT was arranged for Power Line Coupling and for I/O Line Coupling through a capacitive clamp, where applicable. (Note: The I/O coupling test using a capacitive clamp is performed on the I/O interface cables that are longer in length than 3 meters.) A metal ground plane 2.4 meter by 2.0 meter was placed between the floor and the table and is connected to the earth by a 2.0 meter ground rod. The ground rod is connected to the test facility's electrical earth.

## Test Data and Setup Photo

### Environmental Conditions

<b>Temperature:</b>	25 °C
<b>Relative Humidity:</b>	56 %
<b>ATM Pressure:</b>	100.0 kPa

The testing was performed by Jimmy Xiao on 2011-11-27.

Test Mode: Charging & Talking

EN 61000-4-4 Test Points		Test Levels (kV)							
		+0.5	-0.5	+1.0	-1.0	+2.0	-2.0	+4.0	-4.0
AC mains Power input ports	L1	A	A	A	A	/	/	/	/
	L2	A	A	A	A	/	/	/	/
	Earth	/	/	/	/	/	/	/	/
	L1+L2	A	A	A	A	/	/	/	/
	L1 + Earth	/	/	/	/	/	/	/	/
	L2 + Earth	/	/	/	/	/	/	/	/
	L1+L2+Earth	/	/	/	/	/	/	/	/
Signal Port	RJ11	A	A	/	/	/	/	/	/

### Charging mode



### Talking mode



### RJ11 Port



### Base: BER



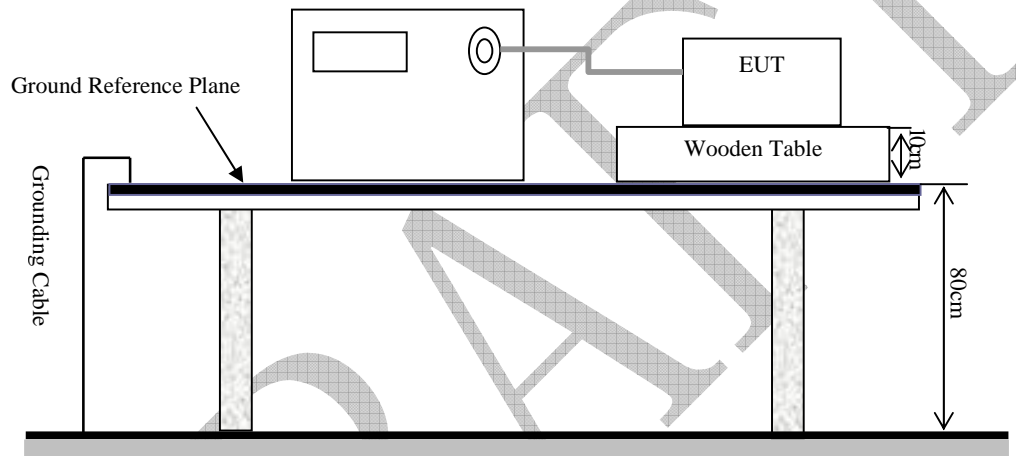
### Test Setup photos

## ETSI EN 301 489-6 V1.3.1 (2008-08) §7.2 - SURGES, COMMON AND DIFFERENTIAL MODE

### Test Equipment

Manufacturer	Description	Model	Serial Number	Calibration Date	Calibration Due Date
EM Test	Ultra Compact Generator	UCS500-N5	V0939105172	2011-07-04	2012-07-03
EM Test	Auto-transformer	MV2616	V0939105173	2011-07-04	2012-07-03

### Test System Setup



### Test Standard

ETSI EN 301 489-1 V1.8.1 / EN 61000-4-5: 2006

AC Mains: L-N: Test level 2 at 1 kV

RJ11 Port: Line-Line: Test level 1 at 0.5 kV

### Test Level

Level	Open Circuit Output Test Voltage $\pm 10\%$
1	0.5 kV
2	1 kV
3	2 kV
4	4 kV
X	Special

Performance Criterion: B

## Test Procedure

- 1) For AC mains port, line to line coupling mode, provide a 1.0kV 1.2/50 us voltage surge (at open-circuit condition), for signal port, line to line coupling mode, provide a 1.0kV 1.2/50 us voltage surge (at open-circuit condition);
- 2) At least 5 positive and 5 negative (polarity) tests with a maximum 1/min repetition rate are conducted during test.
- 3) Different phase angles are done individually.
- 4) Record the EUT operating situation during compliance test and decide the EUT immunity criterion for above each test.

## Test Data and Setup Photo

### Environmental Conditions

Temperature:	25 °C
Relative Humidity:	56 %
ATM Pressure:	100.0 kPa

The testing was performed by Jimmy Xiao on 2011-11-27.

Test Mode: Charging & Talking

Table 1: AC mains power input port

Level	Voltage	Poll	Path	Pass	Fail
1	0.5 kV	±	L-N	A	/
2	1 kV	±	L-N	A	/
3	2 kV	±	L-PE, N-PE	/	/
4	4 kV	±	L-N, L-PE, N-PE	/	/

Table 2: Singal port(RJ11)

Level	Voltage	Poll	Path	Pass	Fail
1	0.5 kV	±	Line-Ground	A	/
2	1 kV	±	Line-Ground	/	/
3	2 kV	±	Line-Ground	/	/
4	4 kV	±	Line-Ground	/	/



### Charging mode



### Talking mode





### Talking RJ11



### Test Setup Photos

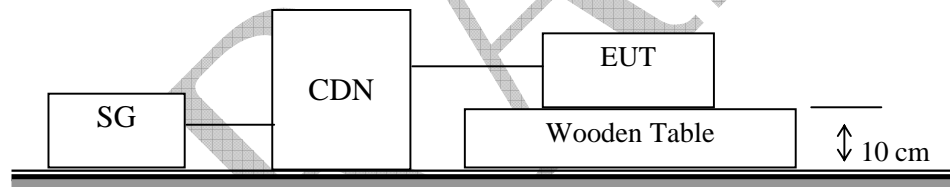
## ETSI EN 301 489-6 V1.3.1 (2008-08) §7.2 - RF COMMON MODE, 0.15 MHz to 80 MHz)

### Test Equipment

Manufacturer	Description	Model	Serial Number	Calibration Date	Calibration Due Date
EM Test	CDN	M3	1201-05	2011-04-28	2012-04-27
EM Test	C/S Tester	CWS500	303277	2011-10-16	2012-10-15
EM Test	Attenuator	6dB	303282	2011-11-15	2012-11-14
EM Test	Attenuator	6dB	303283	N/A	N/A
FCC	Bulk Current Injection Probe	F-120-9A	303284	2011-03-25	2012-03-24
Brüel & Kjær	Ear Simulator	4185	2190351	2011-05-30	2012-05-29
Brüel & Kjær	Telephone Test Head	4602B	2174439	2011-05-30	2012-05-29
LISTEN, Inc.	Microphone Power Supply	N/A	1199-PS165	2011-05-30	2012-05-29
HP	Synthesized Sweeper	8341B	2624A00116	2011-11-07	2012-11-06
BK Precision	Sound Level meter	735	7350087309110025	2011-06-09	2012-06-08

\* **Statement of Traceability:** Bay Area Compliance Laboratories Corp. (Shenzhen) attested that all calibrations have been performed in accordance to NVLAP requirements, traceable to the NIST.

### Test Setup



### Test Standard

ETSI EN 301 489-1 V1.8.1/EN 61000-4-6: 2009  
Test level 2 at 3 V (e.m.f.), 0.15 MHz ~ 80 MHz,

### Test Level

Level	Voltage Level (r.m.s.) (V)
1	1
2	3
3	10
X	Special

**Performance Criterion: A\*** (\*Note: "A" stand for, the speech output signal level shall be at least 35 dB less than the reference level recorded before the start of the test. This shall be verified by the procedure in EN 301 489-6 V1.3.1 clause 5.3.2.)

## Test Procedure

- 1) Let the EUT work in test mode and test it.
- 2) The EUT are placed on an insulating support 0.1 m high above a ground reference plane. CDN (coupling and decoupling device) is placed on the ground plane about 0.3 m from EUT. Cables between CDN and EUT are as short as possible, and their height above the ground reference plane shall be between 30 and 50 mm (where possible).
- 3) The disturbance signal described below is injected to EUT through CDN.
- 4) The EUT operates within its operational mode(s) under intended climatic conditions after power on.
- 5) The frequency range is swept from 150 kHz to 80 MHz using 3V signal level, and with the disturbance signal 80% amplitude modulated with a 1 kHz sine wave.
- 6) The rate of sweep shall not exceed  $1.5 \times 10^{-3}$  decades/s. Where the frequency is swept incrementally, the step size shall not exceed 1% of the start and thereafter 1% of the preceding frequency value.
- 7) Recording the EUT operating situation during compliance testing and decide the EUT immunity criterion.

## Test Data and Setup Photo

### Environmental Conditions

<b>Temperature:</b>	25 °C
<b>Relative Humidity:</b>	56 %
<b>ATM Pressure:</b>	100.0 kPa

*The testing was performed by Jimmy Xiao on 2011-11-27.*

*Test mode: Charging & Talking*

**AC mains input port**

**Frequency range:** 150 kHz to 80 MHz

**Modulation:** Amplitude 80%, 1 kHz sine wave

**Test level:** 3V r.m.s., unmodulated

Level	Voltage Level (r.m.s.) (U <sub>0</sub> )	Pass	Fail
1	1	/	/
2	3	A	/
3	10	/	/
X	Special	/	/

Note: During the test, the Bit Error Ratio is less than  $1 \times 10^{-3}$ .

BER less or equal than  $1 \times 10^{-3}$  during the test

If the equipment contains analogue speech circuits the speech output signal level shall be at least 35 dB less than the reference level recorded before the start of the test. (However, in case of equipment containing analogue speech circuits, instead of BER the assessment of the speech output signal level is used.)

No loss of user control functions or stored data and maintained communication link during and after the tests

No unintentional transmission

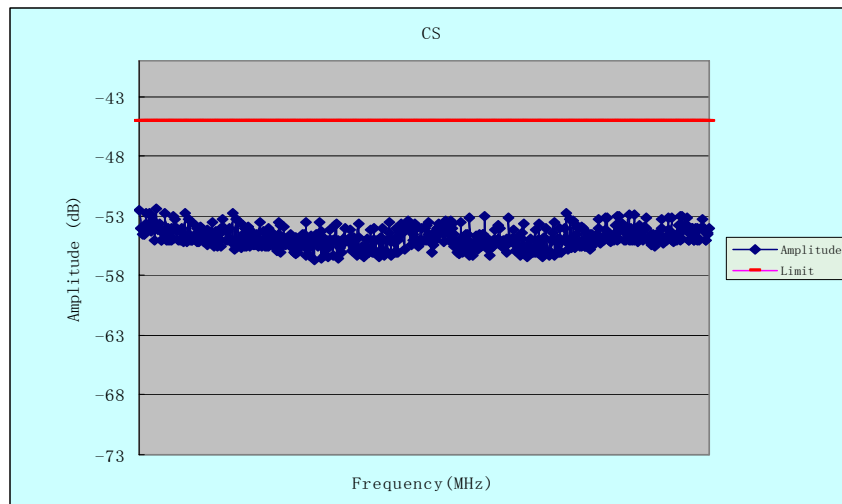
Talking mode data as below:

SPL(worst case) for test result as follows:

**Uplink:**

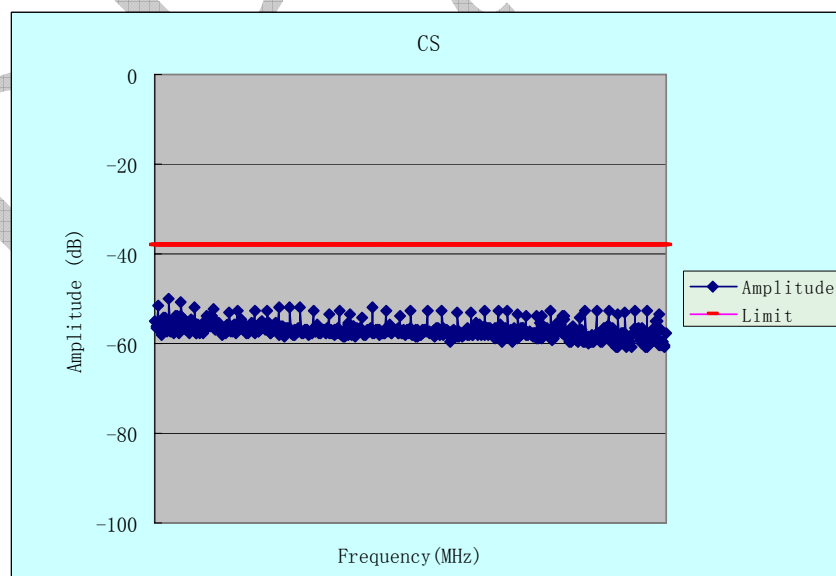
The reference level is -10 dB be equivalent to (-5 dBPa at 1 kHz applied to the mouth reference point).

The plots for worst case as follows:

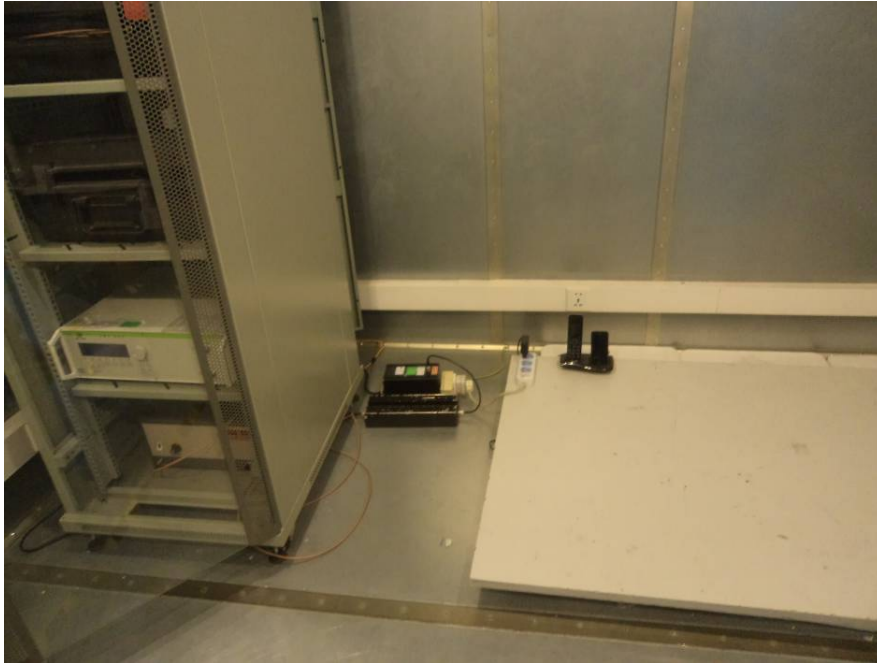


**Downlink:**

The reference level is -3 dB, be equivalent to (0 dBPa at 1 kHz, applied to the ear reference point in the receive path). The plots for worst case as follows:



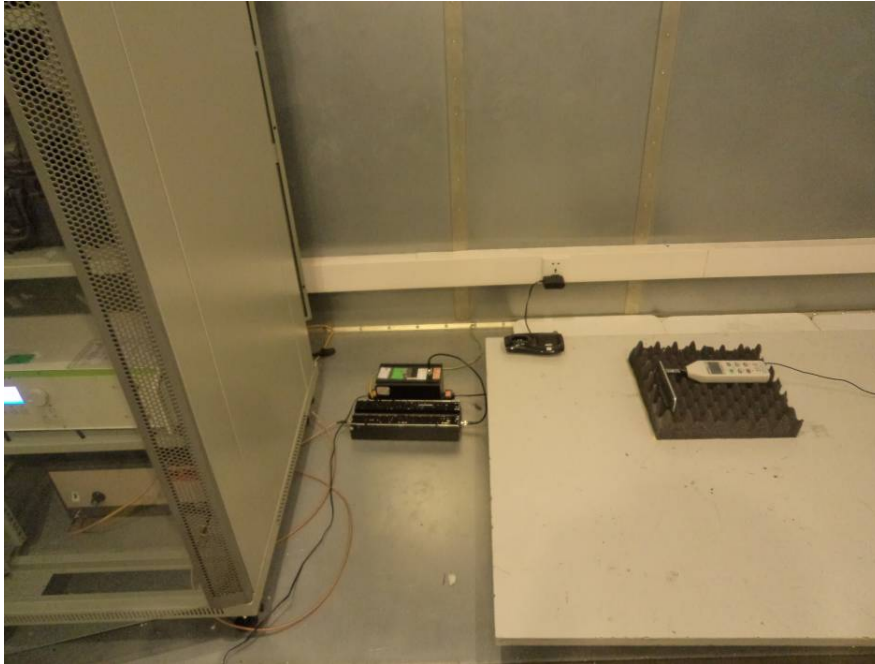
### Charging mode



### Talking mode-AC Mains



**Talking mode-RJ11 Port**



**Base :TBR6 (BER)**



**Test Setup Photos**

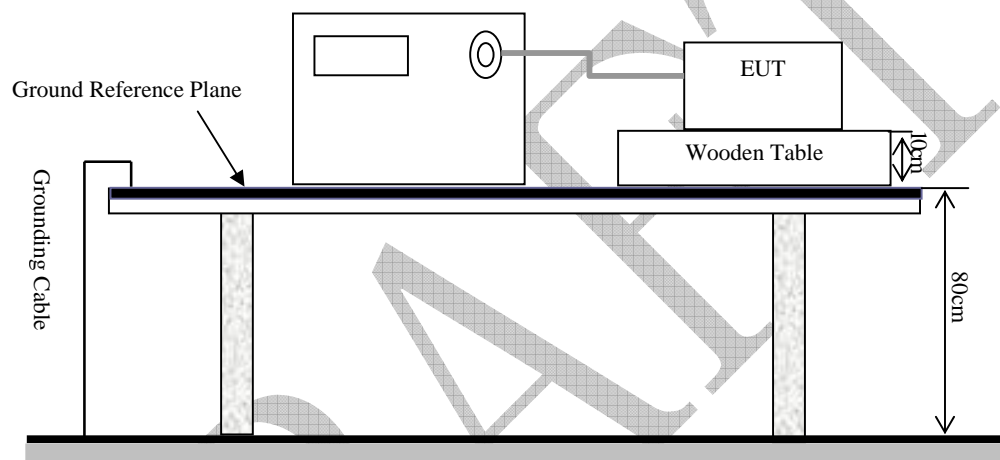


## ETSI EN 301 489-6 V1.3.1 (2008-08) §7.2 - VOLTAGE DIPS AND INTERRUPTIONS

### Test Equipment

Manufacturer	Description	Model	Serial Number	Calibration Date	Calibration Due Date
EM Test	Ultra Compact Generator	UCS500-N5	V0939105172	2011-07-04	2012-07-03
EM Test	Auto-transformer	MV2616	V0939105173	2011-07-04	2012-07-03

### Test System Setup



### Test Standard

ETSI EN 301 489-1 V1.8.1/EN 61000-4-11: 2004  
Test levels and Performance Criterion

### Test Level

Test Level	Voltage dip and short interruptions %UT	Duration (in period)	Performance criterion:
1	0	0.5	B
2	0	1	B
3	70	25	C
4	0	250	C



## Test Procedure

- 1) The interruption is introduced at selected phase angles with specified duration.
- 2) Record any degradation of performance.

## Test Data and Setup Photo

### Environmental Conditions

<b>Temperature:</b>	25 °C
<b>Relative Humidity:</b>	56 %
<b>ATM Pressure:</b>	100.0 kPa

The testing was performed by Jimmy Xiao on 2011-11-27.

Test Mode: Charging

Level	Voltage dip and short interruptions (%)	Td (Periods)	Phase Angle	N	Pass	Fail
1	0	0.5	0/90/180/270	3	A	/
2	0	1	0/90/180/270	3	A	/
3	70	25	0/90/180/270	3	B	/
4	0	250	0/90/180/270	3	B	/

Test Mode: Talking

Level	Voltage dip and short interruptions (%)	Td (Periods)	Phase Angle	N	Pass	Fail
1	0	0.5	0/90/180/270	3	A	/
2	0	1	0/90/180/270	3	B	/
3	70	25	0/90/180/270	3	C	/
4	0	250	0/90/180/270	3	C	/

### Charging mode



### Talking mode



### Test Setup photos

## EXHIBIT A - EUT PHOTOGRAPHS

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**Base:**

**EUT – Front View**



**EUT – Rear View**



**EUT – Cover off View**



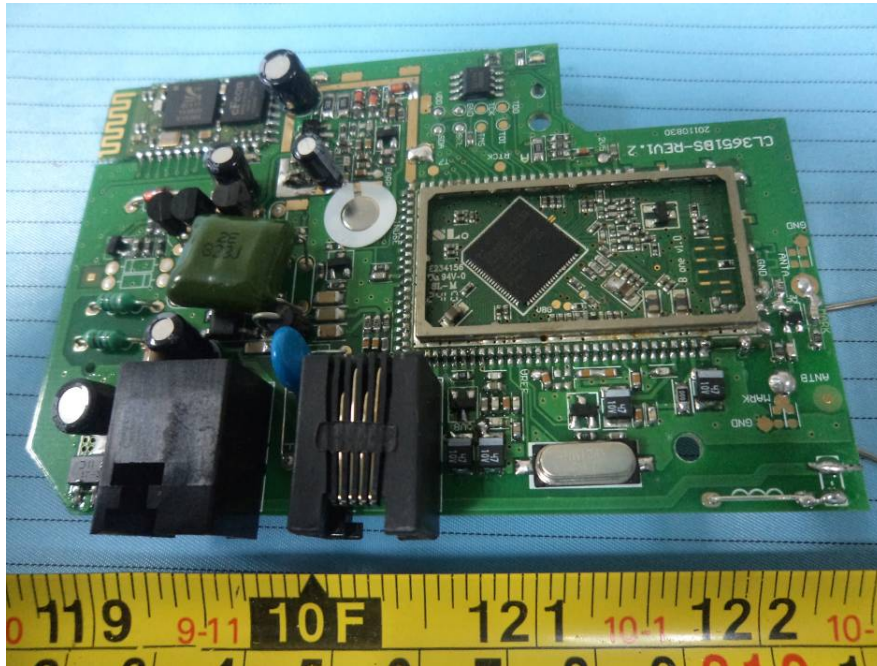
**EUT – Main Board Top View**



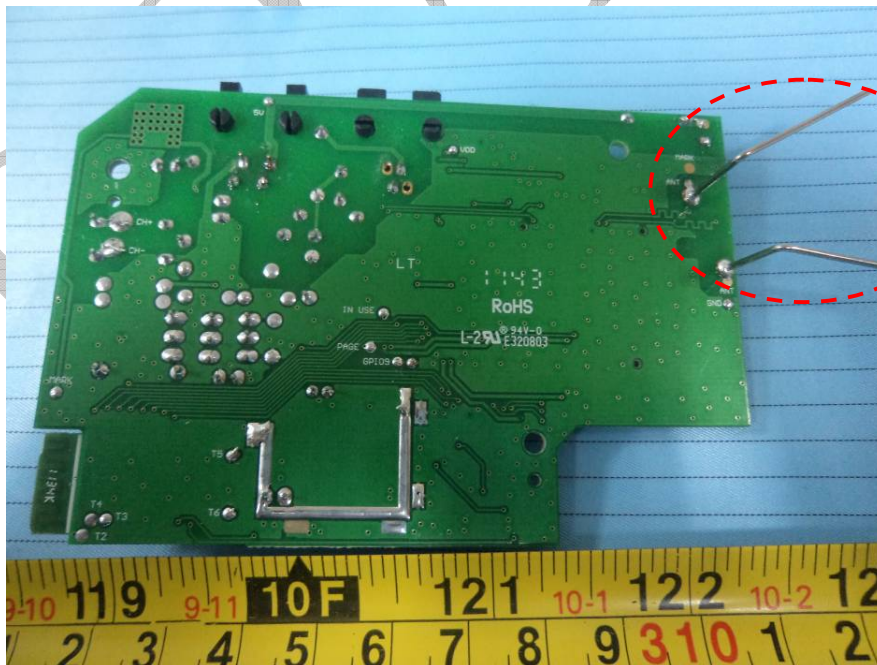
BT Antenna



**EUT – Main Board Top Shielding off View**

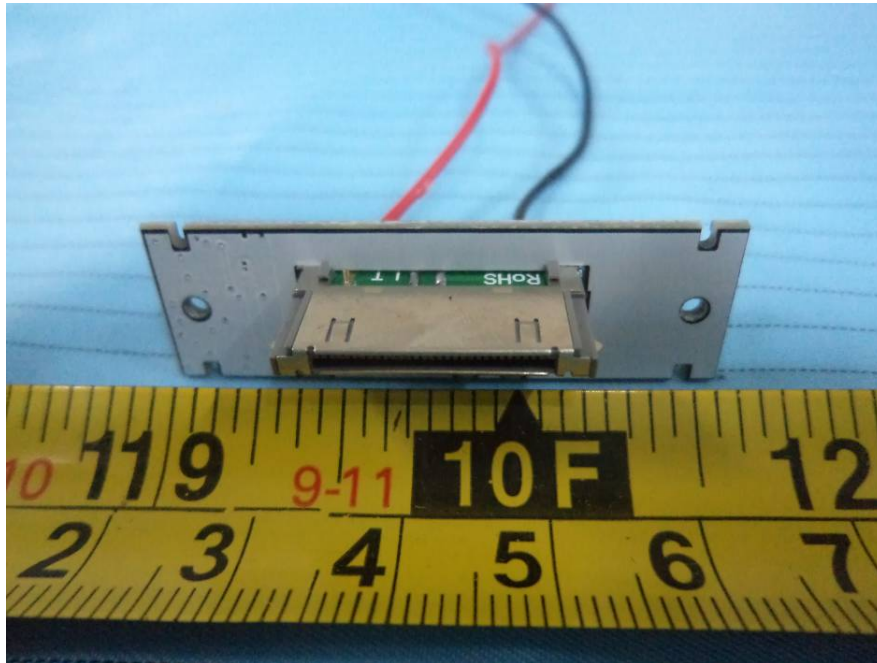


**EUT – Main Board Bottom View**



DECT Antenna

**EUT – iPhone Charging Board Top View**



**EUT – iPhone Charging Board Bottom View**



### EUT – Adapter View



### EUT – Adapter Label View





Handset:

**EUT – Front View**



**EUT – Rear View**





**EUT – Bottom View**



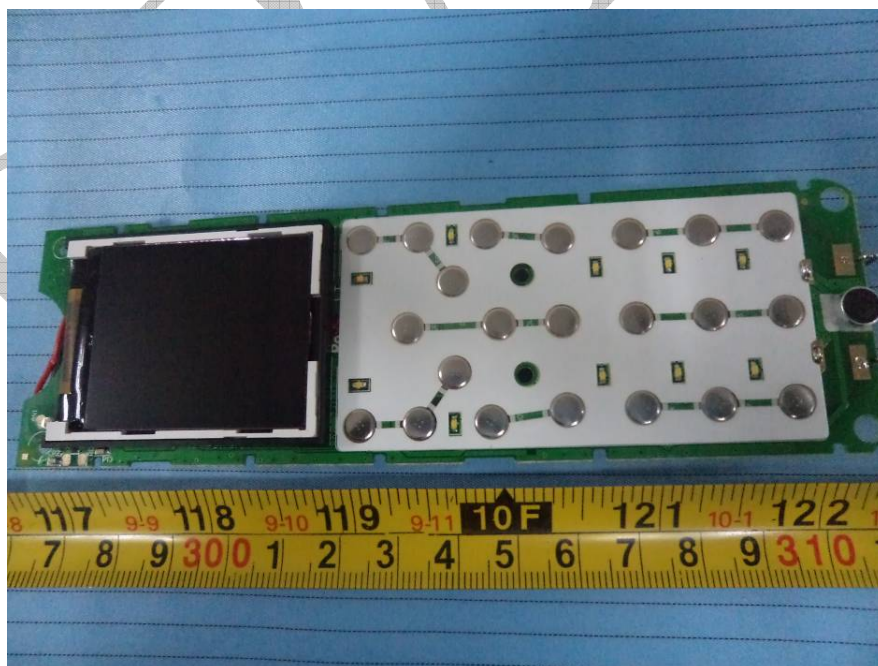
**EUT – Battery off View**



**EUT – Cover off View**

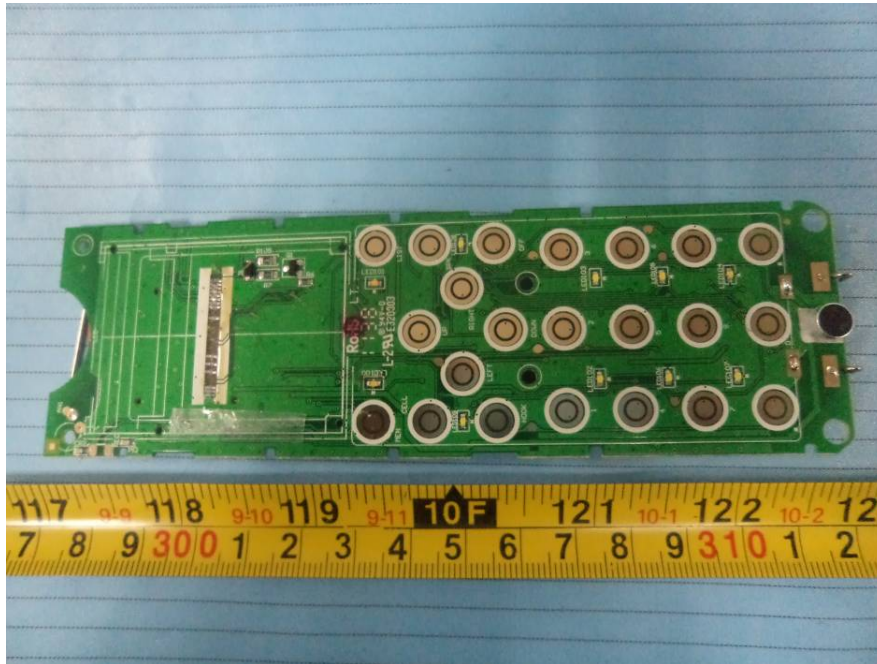


**EUT – Main Board Top View**

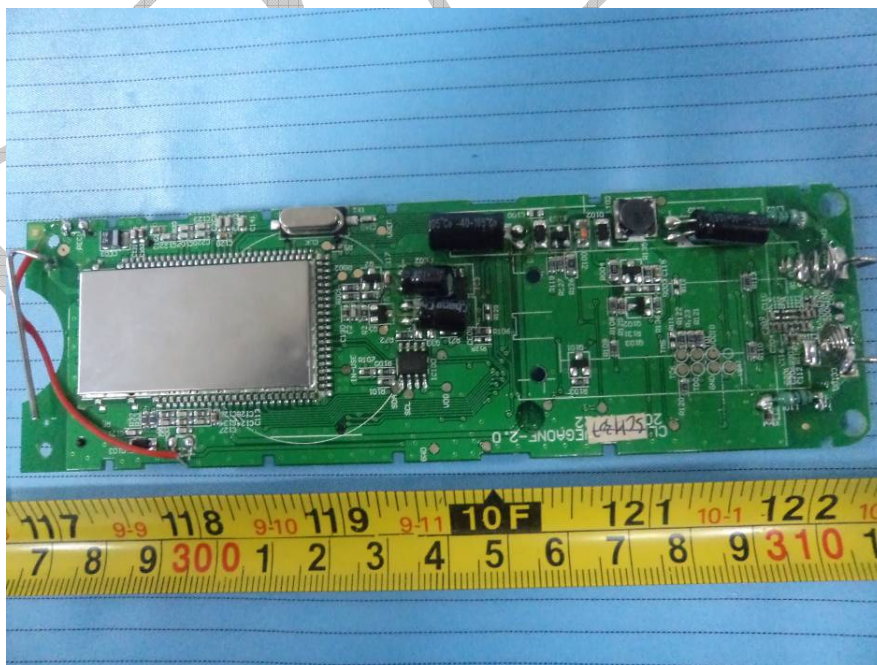




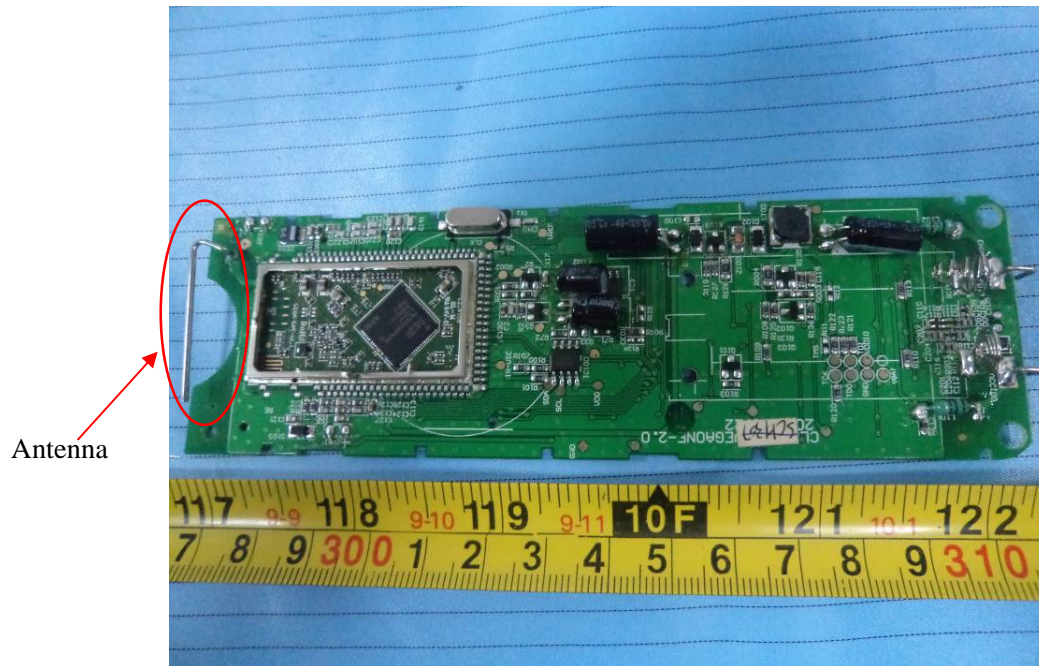
**EUT – Main Board Remove LCD Top View**



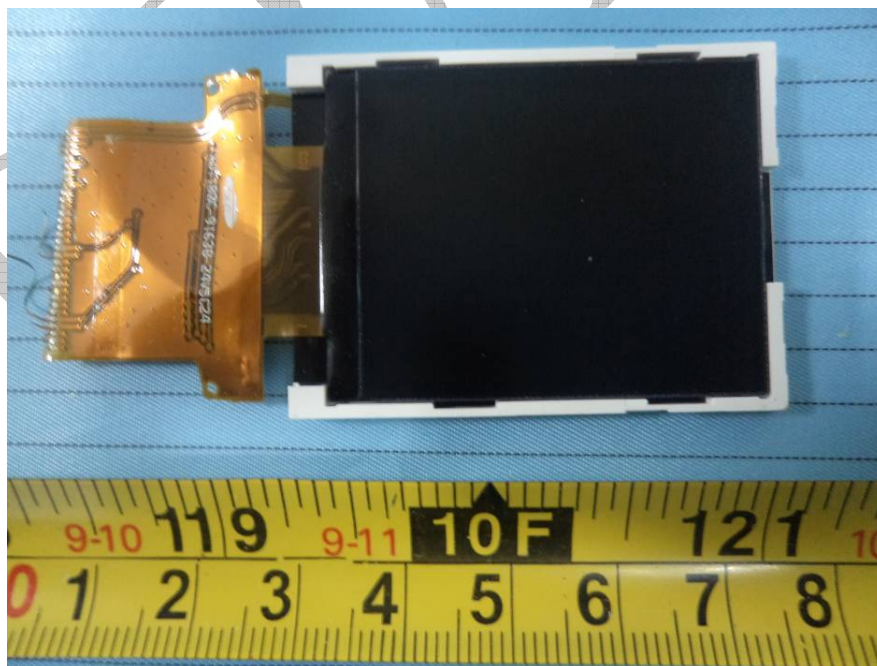
**EUT – Main Board Bottom View**



**EUT – Main Board Shielding off Bottom View**



**EUT – LCD Top View**

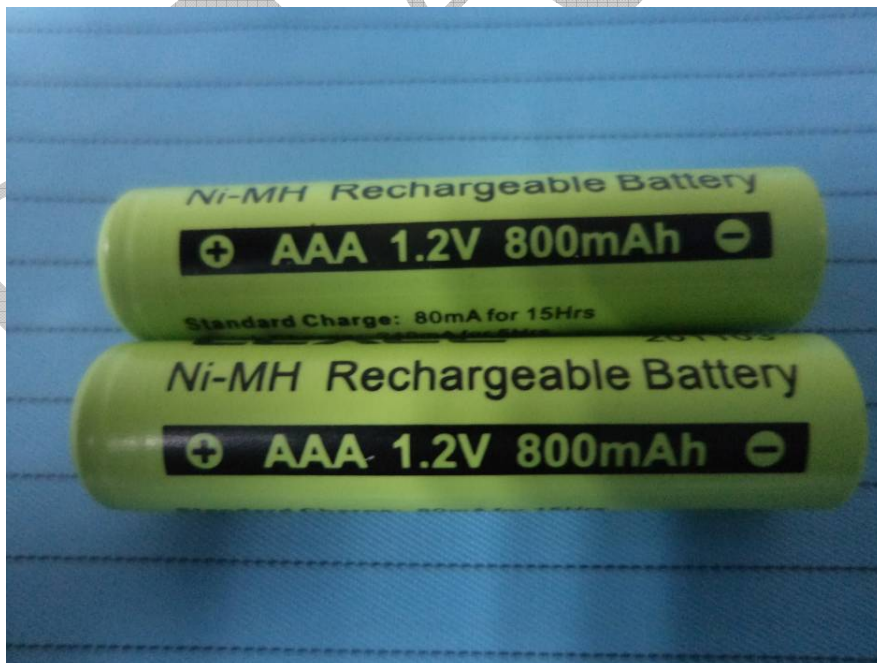




**EUT – LCD Bottom View**

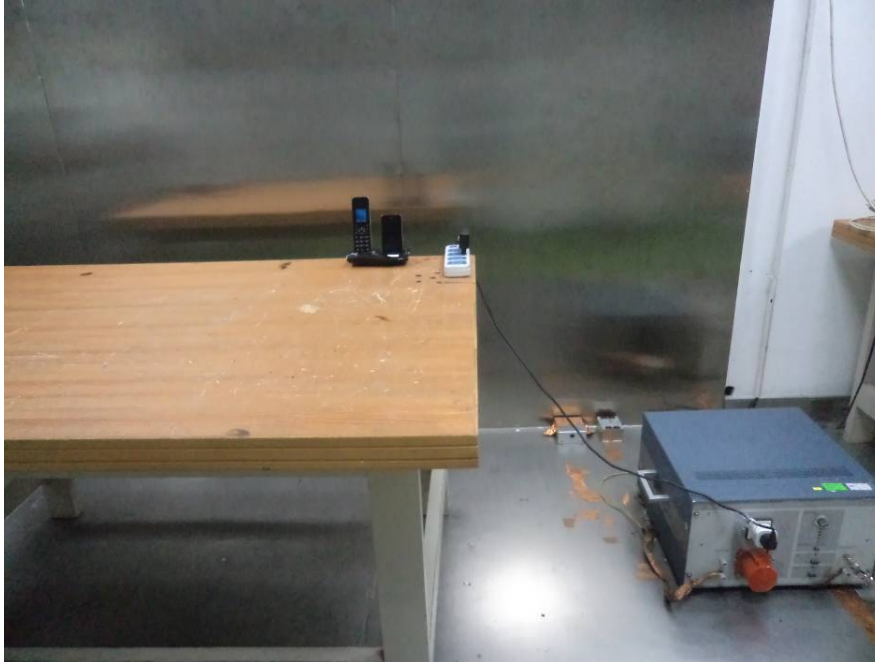


**EUT – Battery View**



## **EXHIBIT B – TEST SETUP PHOTOGRAPHS**

**Conducted Emissions - Front View (Charging mode)**



**Conducted Emissions - Side View (Charging mode)**



**Conducted Emissions - Front View (Talking mode)**



**Conducted Emissions - Side View (Talking mode)**





**Conducted Emissions - Front View (RJ11 Port)**

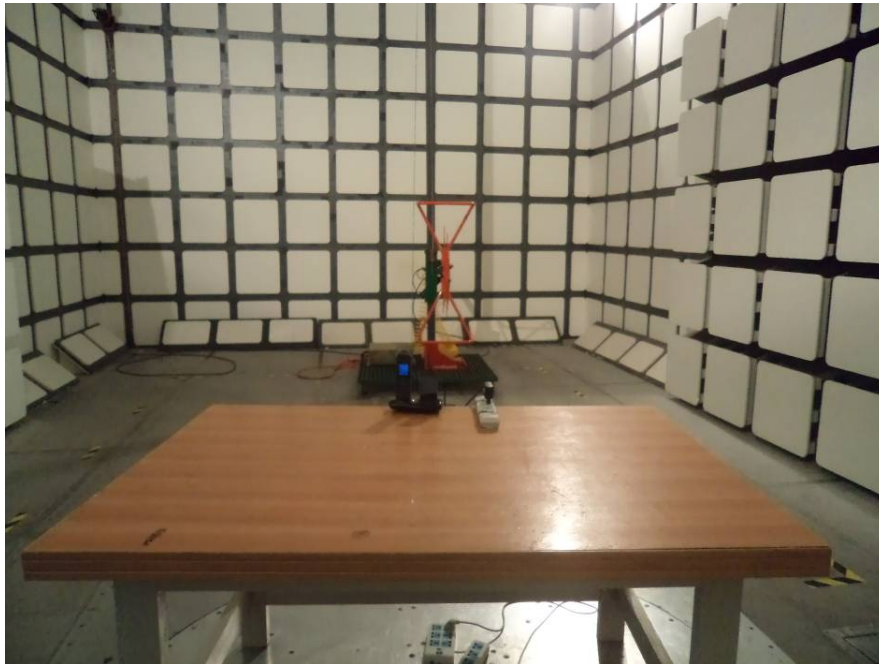


**Conducted Emissions - Side View (RJ11 Port)**

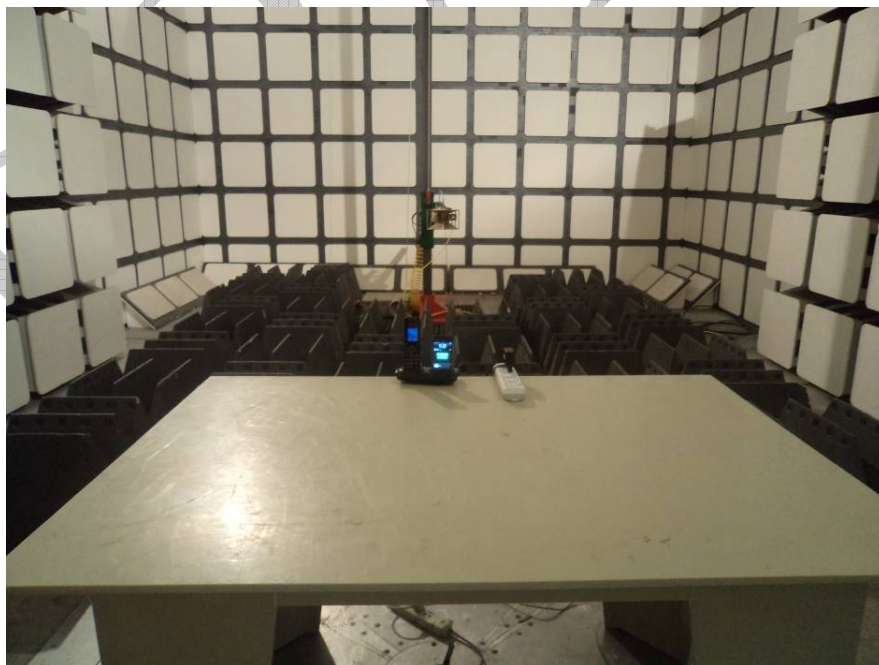




**Below 1 GHz: Radiated Emissions**



**Above 1 GHz: Radiated Emissions**



**\*\*\*\*END OF REPORT\*\*\*\***